

General Description

The MAX1907A/MAX1981A are single-phase, Quick-PWM™ master controllers for IMVP-IV™ CPU core supplies. Multi-phase operation is achieved using a Quick-PWM slave controller (MAX1980). Multiphase operation reduces input ripple current requirements and output voltage ripple while easing component selection and layout difficulties. The MAX1907A/ MAX1981A include active voltage positioning with adjustable gain and offset, reducing power dissipation and bulk output capacitance requirements.

The MAX1907A/MAX1981A are intended for two different notebook CPU core applications: either bucking down the battery directly, or 5V system supply to create the core voltage. The single-stage conversion method allows these devices to directly step down high-voltage batteries for the highest possible efficiency. Alternatively, two-stage conversion (stepping down the 5V system supply instead of the battery) at higher switching frequency provides the minimum possible physical size.

The MAX1907A/MAX1981A meet the IMVP-IV specifications and include logic to interface with the CPU power good signals from the VCCP and VCCMCH rails within the system. The regulator features power-up sequencing, automatically ramping up to the Intel-specified boot voltage. The MAX1907A/MAX1981A feature independent four-level logic inputs for setting the boot voltage (B0-B2) and the suspend voltage (S0-S2).

The MAX1907A/MAX1981A include output undervoltage protection, thermal protection, and system power-OK (SYSPOK) input/output. When any of these protection features detect a fault, the MAX1907A/MAX1981A immediately shut down. Additionally, the MAX1907A includes overvoltage protection.

The MAX1907A/MAX1981A are available in a thin 40-pin QFN package.

Applications

IMVP-IV™ Notebook Computers Single-Phase CPU Core Supply Multiphase CPU Core Supply Voltage-Positioned Step-Down Converters Servers/Desktop Computers

Typical Operating Circuit appears at end of data sheet.

Quick-PWM is a trademark of Maxim Integrated Products, Inc. IMVP-IV is a trademark of Intel Corp.

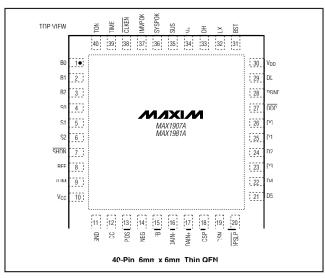
Features

- Quick-PWM Master Controllers
- **♦** Multiphase Conversion with Slave Controller (MAX1980)
- ♦ Active Voltage Positioning with Adjustable Gain and Offset
- **♦** Adjustable Slew Rate Control
- ♦ ±0.75% Vout Accuracy Over Line, Load, and **Temperature**
- ♦ 6-Bit On-Board DAC (16mV Increments)
- ♦ 0.700V to 1.708V Output Adjust Range
- ♦ Selectable 200kHz/300kHz/550kHz/1000kHz Switching Frequency
- ♦ 2V to 28V Battery Input Voltage Range
- **♦ Drive Large Synchronous Rectifier MOSFETs**
- ♦ Output Overvoltage Protection (MAX1907A Only)
- ♦ Undervoltage and Thermal Fault Protection
- ♦ Power Sequencing and Selectable Boot Voltage
- ♦ Low-Profile 40-Pin Thin QFN, 6mm × 6mm **Package**

Ordering Information

PART	TEMP RANGE	PIN-PACKAGE
MAX1907AETL	-40°C to +100°C	40-QFN Thin 6mm x 6mm
MAX1981AETL	-40°C to +100°C	40-QFN Thin 6mm x 6mm

Pin Configuration



Maxim Integrated Products 1

ABSOLUTE MAXIMUM RATINGS

V+ to GND	0.3V to +30V	BST
V _{CC} , V _{DD} to GND	0.3V to +6V	LX to
SYSPOK, IMVPOK, CLKEN to GND	0.3V to +6V	GNE
DPSLP, SUS, D0-D5 to GND	0.3V to +6V	REF
REF, ILIM, CSP, CSN to GND	$-0.3V$ to $(V_{CC} + 0.3V)$	Cont
FB, POS, NEG, OAIN+, CC		40
OAIN- to GND	-0.3V to (V _{CC} + 0.3V)	(d
B0-B2, S0-S2, TON,		Ope
TIME to GND	-0.3V to (V _{CC} + 0.3V)	Juno
DL, DDO, to PGND	$-0.3V$ to $(V_{DD} + 0.3V)$	Stora
DH to LX	$-0.3V$ to $(V_{BST} + 0.3V)$	Lead
SHDN to GND	0.3 to +18V	

BST to GNDLX to BST	6V to +0.3V
GND to PGND	
REF Short-Circuit Duration	Continuous
Continuous Power Dissipation	
40-Pin 6mm × 6mm Thin QFN	
(derate 26.3mW/°C above +70°C)	2105mW
Operating Temperature Range	40°C to +100°C
Junction Temperature	+150°C
Storage Temperature	65°C to +150°C
Storage Temperature (soldering, 10s)	

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

ELECTRICAL CHARACTERISTICS

(Circuit of Figure 1, V+ = 15V, V_{CC} = V_{DD} = V_{SHDN} = V_{TON} = V_{DPSLP} = V_{BI} = V_{OAIN}- = 5V, V_{FB} = V_{CSP} = V_{CSN} = V_{OAIN}+ = V_{NEG} = V_{POS} = 1.26V, ILIM = V_{CC}, SUS = D5 = D1 = D0 = S0 = S1 = S2 = B0 = GND, V_{D4} = V_{D3} = V_{D2} = 1V, V_{B2} = 2V. **T_A = 0°C to +85°C**, unless otherwise specified.)

PARAMETER	SYMBOL	CONI	DITIONS	MIN	TYP	MAX	UNITS
PWM CONTROLLER							
Input Voltage Penge		Battery Voltage, V+		2		28	V
Input Voltage Range		V _{CC} , V _{DD}		4.5		5.5	V
			DAC codes from 1.276V to 1.708V	-0.75		+0.75	
DC Output Voltage Accuracy		V+ = 4.5V to 28V, includes load regulation error	DAC codes from 0.844V to 1.260V	-1.25		+1.25	%
		regulation enter	DAC codes from 0.444V to 0.828V	-3.0		+3.0	
Line Regulation Error		$V_{CC} = 4.5V \text{ to } 5.5V, V_{CC}$	V + = 4.5V to 28V		5		mV
January Diag Comment	I _{FB}	FB		-1		+1	μΑ
Input Bias Current	IPOS, INEG	POS, NEG	-0.2		+0.2	μΑ	
POS, NEG Common-Mode Range		DPSLP = GND		0		2	V
POS, NEG Differential Range		V _{POS} - V _{NEG} , DPSLP	= GND	-200		+200	mV
POS, NEG Offset Gain	AOFF	$\Delta V_{FB}/(V_{POS} - V_{NEG}),$ 100mV, $\overline{DPSLP} = GN$	0.95	1.00	1.05	mV/mV	
POS, NEG Enable Time		Measured from the till the time in which POS in the set point (VDAC		0.1		μs	
		640kHz nominal, R _{TIME} = 23.5kΩ		580	640	700	
TIME Frequency Accuracy		320kHz nominal, $R_{TIME} = 47k\Omega$		295	320	345	kHz
		64kHz nominal, R _{TIM}	$E = 235k\Omega$	58	64	70	

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ELECTRICAL CHARACTERISTICS (continued)

(Circuit of Figure 1, V+ = 15V, $V_{CC} = V_{DD} = V_{\overline{SHDN}} = V_{TON} = V_{\overline{DPSLP}} = V_{BI} = V_{OAIN} = 5V$, $V_{FB} = V_{CSP} = V_{CSN} = V_{OAIN} = V_{NEG} = V_{POS} = 1.26V$, $ILIM = V_{CC}$, SUS = D5 = D1 = D0 = S0 = S1 = S2 = B0 = GND, $V_{D4} = V_{D3} = V_{D2} = 1V$, $V_{B2} = 2V$. **T_A = 0°C to +85°C**, unless otherwise specified.)

PARAMETER	SYMBOL	C	MIN	TYP	MAX	UNITS	
		$V + = 5V, V_{FB} = 1$ (1000kHz)	.2V, TON = GND	250	270	290	
On-Time (Note 1)	ton	101	TON = REF (550kHz)	165	190	215	ns
		V + = 12V, $V_{FB} = 1.2V$	TON = open (300kHz)	320	355	390	
		VFB = 1.2V	$TON = V_{CC} = (200kHz)$	465	515	565	
		TON = GND (100	00kHz)		300	375	ns
Minimum Off-Time (Note 1)	toff(MIN)	TON = V _{CC} , oper or 550kHz)	n or REF (200kHz, 300kHz,		400	475	ns
DDO Delay Time	t _{DDO}		ne time FB reaches the 0-S2, clock speed set by		32		clks
SKIP Delay Time	tskip		ne time when DDO is me in which the controller oping operation		30		clks
BIAS AND REFERENCE							
Quiescent Supply Current (V _{CC})	Icc	Measured at V _{CC} regulation point	s, FB forced above the		1.3	2.0	mA
Quiescent Supply Current (VDD)	I _{DD}	Measured at V _{DD} regulation		0.1	5	μΑ	
Quiescent Battery Supply Current (V+)	I _{V+}	Measured at V+			21	40	μΑ
Shutdown Supply Current (VCC)		Measured at V _{CC}	s, SHDN = GND		0.1	5	μΑ
Shutdown Supply Current (VDD)		Measured at VDD	, SHDN = GND		0.1	5	μΑ
Shutdown Battery Supply Current (V+)		Measured at V+, V _{CC} = V _{DD} = 0 or			0.1	5	μΑ
Reference Voltage	V _{REF}	$V_{CC} = 4.5V \text{ to } 5.5$	5V, I _{REF} = 0	1.990	2.000	2.010	V
Reference Load Regulation	ΔV_{REF}	$I_{REF} = -10\mu A$ to 1	00μΑ	-10		+10	mV
FAULT PROTECTION							
Output Overvoltage Protection Threshold			with respect to unloaded AC code = 0.7V to 1.708V	13	16	19	%
Output Overvoltage Propagation Delay	tovp	FB forced 2% ab		10		μs	
Output Undervoltage Protection Threshold		With respect to up DAC Code = 0.7	67	70	73	%	
Output Undervoltage Propagation Delay	tuvp	FB forced 2% be		10		μs	
Output Fault Blanking Time	t _{BLANK}	The clock speed	is set by R _{TIME} (Note 2)		32		clks



ELECTRICAL CHARACTERISTICS (continued)

(Circuit of Figure 1, $V_{+} = 15V$, $V_{CC} = V_{DD} = V_{\overline{SHDN}} = V_{TON} = V_{\overline{DPSLP}} = V_{BI} = V_{OAIN^{-}} = 5V$, $V_{FB} = V_{CSP} = V_{CSN} = V_{OAIN^{+}} = V_{NEG} = V_{POS} = 1.26V$, $ILIM = V_{CC}$, SUS = D5 = D1 = D0 = S0 = S1 = S2 = B0 = GND, $V_{D4} = V_{D3} = V_{D2} = 1V$, $V_{B2} = 2V$. **T_A = 0°C to +85°C**, unless otherwise specified.)

PARAMETER	SYMBOL	COND	MIN	TYP	MAX	UNITS	
IMVPOK, CLKEN Threshold		SYSPOK = V _{CC} ; measured at FB with	Lower threshold (undervoltage)	-12	-10	-8	%
INVEOR, CEREN THESHOLD		respect to unloaded output voltage	Upper threshold (overvoltage)	8	10	12	/0
CLKEN Delay	tCLKEN	FB in regulation, measedge of SYSPOK	sured from the rising	30	50	90	μs
IMVPOK, CLKEN Transition Blanking Time		Measured from the tin the voltage set by the speed set by R _{TIME}			32		clks
IMVPOK Delay	timvpok	FB in regulation, measedge of CLKEN	sured from the falling	3	5	7	ms
IMVPOK, CLKEN, Output Low Voltage		I _{SINK} = 3mA				0.3	V
IMVPOK, CLKEN, Leakage Current		High state, IMPOK, C	LKEN forced to 5.5V			1	μΑ
V _{CC} Undervoltage Lockout Threshold	Vuvlo(vcc)	Rising edge, hysteres PWM disabled below		4.0		4.4	V
Thermal Shutdown Threshold		Hysteresis = 10°C			160		°C
CURRENT LIMIT							
Current-Limit Threshold Voltage (Positive, Default)		CSP - CSN, ILIM = VC	CC	47	50	53	mV
Current-Limit Threshold Voltage		CSP - CSN	VILIM = 0.3V	27	30	33	mV
(Positive, Adjustable)		031 - 0311	V _{ILIM} = 1V	97	100	103	IIIV
Current-Limit Threshold Voltage (Negative)		$\frac{\text{CSP - CSN; ILIM} = V_C}{\overline{\text{DPSLP}} = V_{CC}}$	CC, SUS = GND and	-68	-63	-58	mV
Current-Limit Threshold Voltage (Zero Crossing)		GND - LX; SUS = VCC	or DPSLP = GND		4		mV
CSP, CSN Input Ranges				0		2	V
CSP, CSN Input Current		$V_{CSP} = V_{CSN} = 0 \text{ to } 5$	V	-1		+1	μΑ
ILIM Input Current		$V_{ILIM} = 0 \text{ to } 5V$			0.01	200	nA
Current-Limit Default Switchover Threshold		ILIM	3	V _{CC} - 1	V _C C - 0.4	V	
GATE DRIVERS							
DH Gate-Driver On-Resistance	Ron(dh)	BST - LX forced to 5V			1.2	4.0	Ω
DL Gate-Driver On-Resistance	Ron(DL)	High state (pullup)			1.2	4.0	Ω
DE Gato Briver of Hodiotario	' 'ON(DL)	Low state (pulldown)			0.5	1.5	22
DH Gate-Driver Source/Sink Current		DH forced to 2.5V, BS		1.6		А	
DL Gate-Driver Sink Current		DL forced to 2.5V		4		Α	

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ELECTRICAL CHARACTERISTICS (continued)

(Circuit of Figure 1, V+ = 15V, $V_{CC} = V_{DD} = V_{\overline{SHDN}} = V_{TON} = V_{\overline{DPSLP}} = V_{BI} = V_{OAIN} = 5V$, $V_{FB} = V_{CSP} = V_{CSN} = V_{OAIN} = V_{NEG} = V_{POS} = 1.26V$, $ILIM = V_{CC}$, SUS = D5 = D1 = D0 = S0 = S1 = S2 = B0 = GND, $V_{D4} = V_{D3} = V_{D2} = 1V$, $V_{B2} = 2V$. **T_A = 0°C to +85°C**, unless otherwise specified.)

PARAMETER	SYMBOL	CONDITIONS			MIN	TYP	MAX	UNITS
DL Gate-Driver Source Current		DL forced to 2.5V				2		А
D 1.T		DL rising	DL rising			35		
Dead Time		DH rising				26		ns
VOLTAGE-POSITIONING AMPL	IFIER				•			
Input Offset Voltage	Vos	$V_{CM} = 0$			-1		+1	mV
Input Bias Current	I _{BIAS}	OAIN+, OAIN-				<0.1	200	nA
Op Amp Disable Threshold		OAIN-			3	V _{CC} - 1	V _C C - 0.4	V
Common-Mode Input Voltage Range	Vсм	Guaranteed by CMRR	test		0		2.5	V
Common-Mode Rejection Ratio	CMRR	VOAIN+ = VOAIN- = 0 to	o 2.5V		70	115		dB
Power-Supply Rejection Ratio	PSRR	$V_{CC} = 4.5V \text{ to } 5.5V$			75	100		dB
Large-Signal Voltage Gain	AOA	$R_L = 1k\Omega$ to $V_{CC}/2$			80	112		
Output Voltage Swing		V _{OAIN+} - V _{OAIN-} ≤ 10	mV,	V _C C - V _O H		100	300	mV
Output Voltage Swing		$R_L = 1k\Omega$ to $V_{CC}/2$		V _{OL}		70	200	IIIV
Input Capacitance						11		рF
Gain-Bandwidth Product						3		MHz
Slew Rate						0.3		V/µs
Capacitive-Load Stability		No sustained oscillatio	ns			400		рF
LOGIC AND I/O								
Logic Input High Voltage	VIH	SUS, DPSLP, SHDN, S	YSPOK		2.4			V
Logic Input Low Voltage	VIL	SUS, DPSLP, SHDN, S	YSPOK	(8.0	V
Logic Input Current		SUS, DPSLP, SHDN, S	YSPOK		-1		+1	μΑ
SHDN No Fault Threshold		To enable No-Fault Mo	de		12		15	V
DAC Input High Voltage	Vvid(High)	D0-D5			0.7			V
DAC Input Low Voltage	V _{VID(LOW)}	D0-D5					0.3	V
DAC Input Current		D0-D5			-1		+1	μΑ
Driver-Disable Output High Voltage		DDO, I _{LOAD} = 1mA		2.4			V	
Driver-Disable Output Low Voltage		DDO, I _{LOAD} = 1mA				0.3	V	
			High		V _C C - 0.	4		
		TON 00 00 D0 50	Open)	3.15		3.85	1.7
Four-Level Input Logic Levels		TON, S0-S2, B0-B2	REF		1.65		2.35	V
			Low				0.5	
Four-Level Input Current		TON, S0-S2, B0-B2 fo	rced to	GND or V _C C	-3		+3	μA



ELECTRICAL CHARACTERISTICS

(Circuit of Figure 1, V+ = 15V, $V_{CC} = V_{DD} = V_{\overline{S}H\overline{DN}} = V_{TON} = V_{\overline{DPSLP}} = V_{BI} = V_{OAIN^-} = 5V$, $V_{FB} = V_{CSP} = V_{CSN} = V_{OAIN^+} = V_{NEG} = V_{POS} = 1.26V$, $ILIM = V_{CC}$, SUS = D5 = D1 = D0 = SO = S1 = S2 = B0 = GND, $V_{D4} = V_{D3} = V_{D2} = 1V$, $V_{B2} = 2V$. $T_A = -40^{\circ}C$ to +100°C, unless otherwise specified.)

PARAMETER	SYMBOL	COND	MIN	TYP	MAX	UNITS	
Innut Valtage Dange		Battery voltage, V+		2		28	V
Input Voltage Range		V _{CC} , V _{DD}		4.5		5.5	V
			DAC codes from 1.276V to 1.708V	-1.00		+1.00	
DC Output Voltage Accuracy		V+ = 4.5V to 28V, includes load regulation error	DAC codes from 0.844V to 1.260V	-1.5		+1.5	%
		regulation entit	DAC codes from 0.444V to 0.828V	-3.5		+3.5	
POS, NEG Offset Gain	AOFF	$\Delta V_{FB}/(V_{POS} - V_{NEG}), (100 mV, \overline{DPSLP} = GNI$	(V _{POS} - V _{NEG}) = D	0.95		1.05	mV/mV
		640kHz nominal, RTIN	$_{\text{IE}}$ = 23.5k Ω	580		700	
TIME Frequency Accuracy		320kHz nominal, R _{TIN}	1E = 47kΩ	295		305	kHz
		64kHz nominal, R _{TIME}	= 235kΩ	58		70	
		$V + = 5V, V_{FB} = 1.2V,$ (1000kHz)	TON = GND	250		290	
O. T. (N.) (1)			TON = REF (550kHz)	165		215	
On-Time (Note 1)	ton	V+ = 12V, V _{FB} = 1.2V	TON = open (300kHz)	320		390	ns
			$TON = V_{CC}$ (200kHz)	465		565	
		TON = GND (1000kHz	z)			375	ns
Minimum Off-Time (Note 1)	toff(MIN)	TON = V _{CC} , open, or or 550kHz)	REF (200kHz, 300kHz,			475	ns
BIAS AND REFERENCE	•	•					•
Quiescent Supply Current (V _{CC})	Icc	Measured at V _{CC} , FB regulation point	forced above the			2.0	mA
Quiescent Supply Current (V _{DD})	I _{DD}	Measured at V _{DD} , FB regulation			20	μΑ	
Quiescent Battery Supply Current (V+)	I _{V+}	Measured at V+				40	μΑ
Shutdown Supply Current (VCC)		Measured at V _{CC} , SH	DN = GND			20	μΑ
Shutdown Supply Current (V _{DD})		Measured at V _{DD} , SH	DN = GND			20	μΑ
Shutdown Battery Supply Current (V+)		Measured at V+, SHD V _{CC} = V _{DD} = 0 or 5V				20	μΑ

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ELECTRICAL CHARACTERISTICS (continued)

(Circuit of Figure 1, $V_{+} = 15V$, $V_{CC} = V_{DD} = V_{\overline{SHDN}} = V_{TON} = V_{\overline{DPSLP}} = V_{BI} = V_{OAIN^{-}} = 5V$, $V_{FB} = V_{CSP} = V_{CSN} = V_{OAIN^{+}} = V_{NEG} = V_{POS} = 1.26V$, $ILIM = V_{CC}$, SUS = D5 = D1 = D0 = SO = S1 = S2 = B0 = GND, $V_{D4} = V_{D3} = V_{D2} = 1V$, $V_{B2} = 2V$. $T_{A} = -40^{\circ}C$ to $+100^{\circ}C$, unless otherwise specified.)

PARAMETER	SYMBOL	CONDITIONS			MIN	TYP	MAX	UNITS
Reference Voltage	V _{REF}	$V_{CC} = 4.5V \text{ to } 5.5V, I_{R}$	REF = 0		1.985		2.015	V
FAULT PROTECTION								
Output Overvoltage Protection Threshold		Measured at FB with routput voltage	espect	o unloaded	13		19	%
Output Undervoltage Protection Threshold		With respect to unload	ded outp	out voltage	67		73	%
IMVDOV. CLIVEN Threehold		SYSPOK = V _{CC} ; measured at FB with		hreshold voltage)	-12		-8	%
IMVPOK, CLKEN Threshold		respect to unloaded output voltage		threshold oltage)	+8		+12	%
CLKEN Delay	t <u>CLKEN</u>	FB in regulation, meas	sured fro	om the rising	30			μs
IMVPOK Delay	timvpok	FB in regulation, meas	sured fro	om the falling	3			ms
VCC Undervoltage Lockout Threshold	V _U VLO(VCC)	Rising edge, hysteres disabled below this le		nV, PWM	3.95		4.45	V
CURRENT LIMIT	•				-			
Current-Limit Threshold Voltage (Positive, Default)		CSP - CSN, ILIM = VC	C		45		55	mV
Current-Limit Threshold Voltage		CSP - CSN	V _{ILIM} :	= 0.3V	25		35	mV
(Positive, Adjustable)		CSF - CSN	V _{ILIM} :	= 2V (REF)	95		105	IIIV
Current-Limit Threshold Voltage (Negative)		$\frac{\text{CSP - CSN; ILIM} = V_{C}}{\overline{\text{DPSLP}} = V_{CC}}$	C, SUS	= GND and	-70		-56	mV
GATE DRIVERS								
DH Gate-Driver On-Resistance	Ron(dh)	BST - LX forced to 5V					4.5	Ω
DL Gate-Driver On-Resistance	Ron(dl)	High state (pullup)					4.5	Ω
DE Gare-Direct Oll-Hesistance	I ION(DL)	Low state (pulldown)				2.0	20	
VOLTAGE-POSITIONING AMPLI	1				•			T
Input Offset Voltage	Vos	$V_{CM} = 0$		T	-2		+2	mV
Output Voltage Swing		VOAIN+ - VOAIN- ≤ 10)mV,	VCC - VOH			300	mV
		$R_L = 1k\Omega$ to $V_{CC}/2$		V _{OL}			200	

ELECTRICAL CHARACTERISTICS (continued)

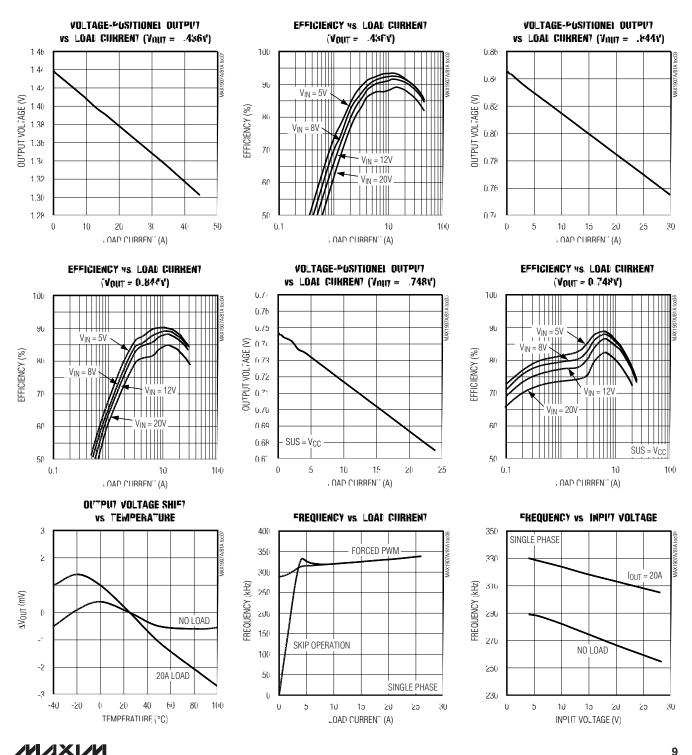
(Circuit of Figure 1, V+ = 15V, $V_{CC} = V_{DD} = V_{\overline{SHDN}} = V_{TON} = V_{\overline{DPSLP}} = V_{BI} = V_{OAIN}$ - = 5V, $V_{FB} = V_{CSP} = V_{CSN} = V_{OAIN}$ + = $V_{NEG} = V_{POS}$ = 1.26V, $ILIM = V_{CC}$, SUS = D5 = D1 = D0 = SO = S1 = S2 = B0 = GND, $V_{D4} = V_{D3} = V_{D2} = 1V$, $V_{B2} = 2V$. **T_A = -40°C to +100°C**, unless otherwise specified.)

PARAMETER	SYMBOL	CONDITIONS		MIN	MAX	UNITS	
Output Voltage Swing		$ V_{OAIN+} - V_{OAIN-} \le 10$)mV,	V _C C – V _O H		300	
Output Voltage Swing		$R_L = 1k\Omega$ to $V_{CC}/2$		V _{OL}		200	
LOGIC AND I/O							
DAC Input High Voltage	Vvid(High)	D0-D5		0.7		V	
DAC Input Low Voltage	V _{VID(LOW)}	D0-D5	D0-D5			0.3	V
			High		V _{CC} - 0.4		
Four Level Input Legis Levels		TON, S0-S2, B0-B2	Open		3.15	3.85	V
Four-Level Input Logic Levels		101N, 30-32, BU-BZ	REF		1.65	2.35	V
			Low			0.5	

- Note 1: On-time specifications are measured from 50% to 50% at the DH pin, with LX forced to GND, BST forced to 5V, and a 500pF capacitor from DH to LX to simulate external MOSFET gate capacitance. Actual in-circuit times may be different due to MOSFET switching speeds.
- Note 2: The output fault blanking time is measured from the time when FB reaches the regulation voltage set by the DAC code. During power-up, the regulation voltage is set by the boot DAC code (B0–B2). During normal operation (SUS = low), the regulation voltage is set by the VID DAC inputs (D0–D5). During suspend mode (SUS = high), the regulation voltage is set by the suspend DAC inputs (S0–S2).
- Note 3: Specifications to T_A = -40°C to +100°C are guaranteed by design and are not production tested.

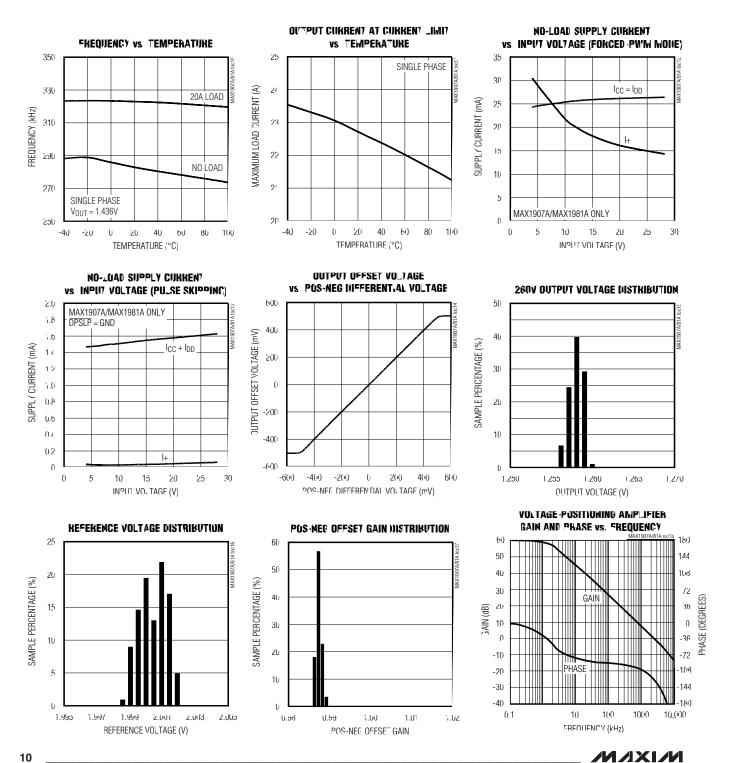
Typical Operating Characteristics

(Circuit of Figure 1, V+ = 12V, V_{CC} = V_{DD} = 5V, B0-B2 set to 1.276V, S0-S2 set to 0.748V.)



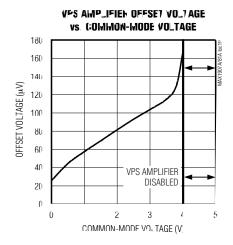
Typical Operating Characteristics (continued)

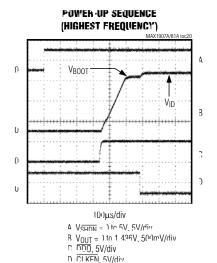
(Circuit of Figure 1, V+ = 12V, $V_{CC} = V_{DD} = 5V$, B0-B2 set to 1.276V, S0-S2 set to 0.748V.)

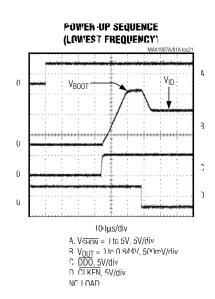


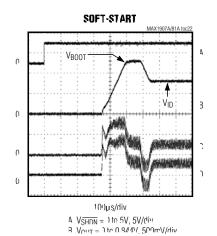
Typical Operating Characteristics (continued)

(Circuit of Figure 1, V+ = 12V, $V_{CC} = V_{DD} = 5V$, B0-B2 set to 1.276V, S0-S2 set to 0.748V.)





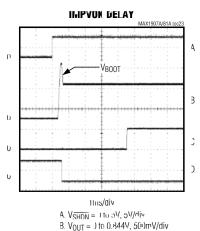


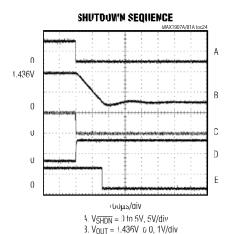


C ILM, 10A/div

D ILS, 10A/div

ROMO LOAD

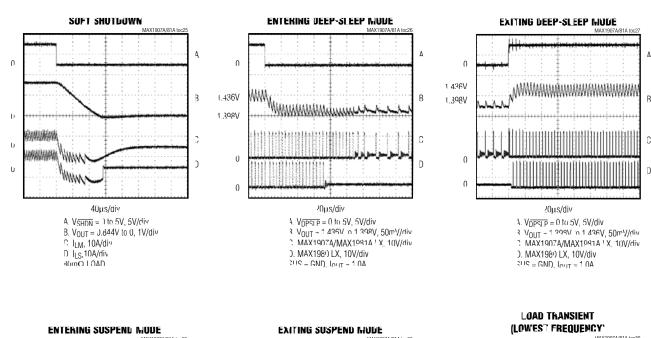


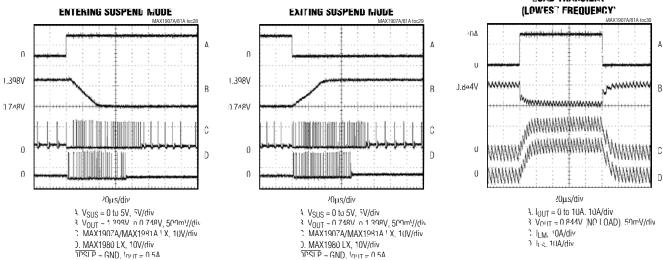


- C. IMPVOK 5V/div

Typical Operating Characteristics (continued)

(Circuit of Figure 1, V+ = 12V, $V_{CC} = V_{DD} = 5V$, B0-B2 set to 1.276V, S0-S2 set to 0.748V.)

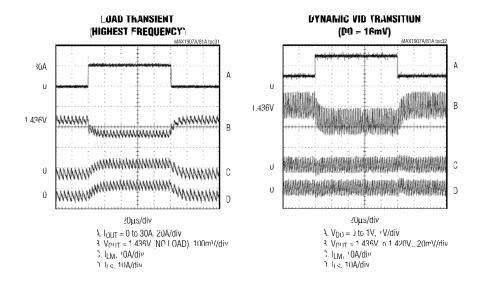


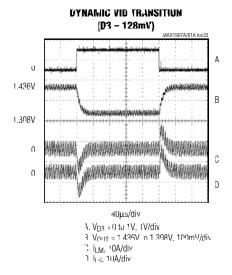


TPSI P = GND, IntIT = 0.5A

Typical Operating Characteristics (continued)

(Circuit of Figure 1, V+ = 12V, V_{CC} = V_{DD} = 5V, B0-B2 set to 1.276V, S0-S2 set to 0.748V.)





Pin Description

PIN	NAME	FUNCTION
1, 2, 3	B0-B2	Boot-Mode Voltage Select Inputs. B0–B2 are four-level digital inputs that select the boot-mode VID code (Table 6) for the boot-mode multiplexer inputs. During power-up, the boot-mode VID code is delivered to the DAC (see the <i>Internal Multiplexers</i> section).
4, 5, 6	S0-S2	Suspend-Mode Voltage Select Inputs. S0–S2 are four-level digital inputs that select the suspend-mode VID code (Table 5) for the suspend-mode multiplexer inputs. If SUS is high, the suspend-mode VID code is delivered to the DAC (see the <i>Internal Multiplexers</i> section).
7	SHDN	Shutdown Control Input. This input cannot withstand the battery voltage. Connect to V_{CC} for normal operation. Connect to ground to put the IC into its $10\mu A$ (max) shutdown state. During the transition from normal operation to shutdown the output voltage is ramped down at the output voltage slew rate programmed by the TIME pin. In shutdown mode, DL is forced to V_{DD} to clamp the output to ground. Forcing \overline{SHDN} to $12V\sim15V$ disables both overvoltage protection and undervoltage protection circuits, and clears the fault latch. Do not connect \overline{SHDN} to $>15V$.
8	REF	2V Reference Output. Bypass to GND with 0.22μF or greater ceramic capacitor. The reference can source 50μA for external loads. Loading REF degrades output voltage accuracy according to the REF load regulation error.
9	ILIM	Current-Limit Adjustment. The current-limit threshold defaults to 50mV if ILIM is tied to V_{CC} . In adjustable mode, the current-limit threshold voltage is precisely 1/10th the voltage seen at ILIM over a 100mV to 1.5V range. The logic threshold for switchover to the 50mV default value is approximately V_{CC} - 1V.
10	Vcc	Analog Supply Voltage Input for PWM Core. Connect V_{CC} to the system supply voltage (4.5V to 5.5V) with a series 10Ω resistor. Bypass to GND with a $1\mu F$ or greater ceramic capacitor, as close to the IC as possible.
11	GND	Analog Ground
12	CC	Integrator Capacitor Connection. Connect a 47pF to 1000pF (270pF typ) capacitor from CC to GND to set the integration time constant.
13	POS	Feedback Offset Adjust Positive Input. The output shifts by 100% (typ) of the differential input voltage appearing between POS and NEG when DPSLP is low. The common-mode range of POS and NEG is 0 to 2V. POS and NEG should be generated from resistor dividers from the output.
14	NEG	Feedback Offset Adjust Negative Input. The output shifts by 100% (typ) of differential input voltage appearing between POS and NEG when DPSLP is low. The common-mode range of POS and NEG is 0 to 2V. POS and NEG should be generated from resistor dividers from the output.
15	FB	Feedback Input. FB is internally connected to both the feedback input and the output of the voltage-positioning op amp (Figure 2). Connect a resistor between FB and OAIN- (Figure 1) to set the voltage-positioning gain (see the <i>Setting Voltage Positioning</i> section).
16	OAIN-	Dual-Mode Op Amp Inverting Input and Op Amp Disable Input. When using the internal op amp for additional voltage-positioning gain (Figure 1), connect to the negative terminal of current-sense resistor through a $1k\Omega \pm 1\%$ resistor as described in the <i>Setting Voltage Positioning</i> section. Connect OAIN- to V_{CC} to disable op amp. The logic threshold to disable the op amp is approximately V_{CC} - $1V$.
17	OAIN+	Op Amp Noninverting Input. When using the internal op amp for additional voltage-positioning gain (Figure 1), connect to the positive terminal of current-sense resistor through a resistor as described in the Setting Voltage Positioning section.
18	CSP	Positive Current-Limit Input. Connect to the positive terminal of the current-sense resistor.

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Pin Description (continued)

PIN	NAME	FUNCTION
19	CSN	Negative Current-Limit Input. Connect to the negative terminal of the current-sense resistor.
20	DPSLP	Deep-Sleep Control Input. When DPSLP is low the system enters the deep-sleep state and the regulator applies the appropriate deep-sleep offset. The MAX1907A/MAX1981A adds the offset measured at the POS and NEG pins to the output. 32 clock cycles after the deep-sleep transition is completed, DDO goes low (see the <i>Driver Disable and Low-Power Pulse Skipping</i> section). Another 32 clock cycles later, the MAX1907A/MAX1981A is allowed to enter pulse-skipping operation.
21–26	D5-D0	Low-Voltage VID DAC Code Inputs. D0 is the LSB, and D5 is the MSB of the internal 6-bit VID DAC (Table 4). The D0–D5 inputs do not have internal pullups. These 1V logic inputs are designed to interface directly with the CPU. In all normal active modes (modes other than suspend and boot), the output voltage is set by the VID code indicated by the D0–D5 logic-level voltages on D0–D5. In suspend mode (SUS = high), the decoded state of the four-level S0–S2 inputs sets the output voltage. In boot mode (see the <i>Power-Up Sequence</i> section), the decoded state of the four-level B0–B2 inputs set the output voltage.
27	DDO	Driver-Disable Output. This TTL-logic output can be used to disable the driver outputs on slave-switching regulator controllers. This forces a high-impedance condition and makes it possible for the MAX1907A/MAX1981A master controller to operate in low current SKIP mode. DDO goes low 32 R _{TIME} clock cycles after the MAX1907A/MAX1981A completes a transition to the suspend mode or deep-sleep voltage (see the <i>Driver Disable and Low-Power Pulse Skipping</i> section). Another 30 clock cycles later, the MAX1907A/MAX1981A enters automatic pulse-skipping operation.
28	PGND	Power Ground. Ground connection for the DL gate driver.
29	DL	Low-Side Gate Driver Output. DL swings from PGND to V _{DD} . DL is forced high after the MAX1907A/MAX1981A powers down (SHDN = GND) or when the controller detects a fault. The MAX1981A does not include overvoltage protection.
30	V _{DD}	Supply Voltage Input for the DL Gate Driver. Connect to the system supply voltage (4.5V to 5.5V). Bypass to PGND with a 1µF or greater ceramic capacitor, as close to the IC as possible.
31	BST	Boost Flying Capacitor Connection. An optional resistor in series with BST allows the DH pullup current to be adjusted.
32	LX	Inductor Connection. LX is the internal lower supply rail for the DH high-side gate driver. It connects to the skip-mode zero-crossing comparator.
33	DH	High-Side Gate Driver. Output swings LX to BST.
34	V+	Battery Voltage Sense Connection. Used only for PWM one-shot timing. DH on-time is inversely proportional to input voltage over a range of 2V to 28V.
35	SUS	Suspend-Mode Control Input. When SUS is high the regulator slews to the suspend voltage level. This level is set with four-level logic signals at the S0–S2 inputs. 32 clock cycles after the transition to the suspend-mode voltage is completed, $\overline{\text{DDO}}$ goes low (see the <i>Driver Disable and Low-Power Pulse Skipping</i> section). Another 32 clock cycles later, the MAX1907A/MAX1981A is allowed to enter pulse-skipping operation.
36	SYSPOK	System Power-Good Input. Primarily, SYSPOK serves as the wired NOR junction of the open-drain power-good signals for the V _{CCP} and V _{CCMCH} supplies. A falling edge on SYSPOK shuts down the MAX1907A/MAX1981A and sets the fault latch. Toggle SHDN or cycle V _{CC} power below 1V to restart the controller.

Pin Description (continued)

COMPONENT

PIN	NAME	FUNCTION
37	IMVPOK	Open-Drain Power Good Output. After output voltage transitions, except during power-up and power-down, if OUT is in regulation then IMVPOK is high impedance. IMVPOK is pulled high whenever the slew-rate control is active (output voltage transitions). IMVPOK is forced low in shutdown. A pullup resistor on IMVPOK will cause additional finite shutdown current. IMVPOK also reflects the state of SYSPOK and includes a 3ms (min) delay for power-up. IMVPOK is forced high during VID transitions.
38	CLKEN	Clock Enable Logic Output. This inverted logic output indicates when SYSPOK is high and the output voltage sensed at FB is in regulation. CLKEN is forced low during VID transitions.
39	TIME	Slew-Rate Adjustment Pin. Connect a resistor from TIME to GND to set the internal slew-rate clock. A 235k Ω to 23.5k Ω resistor sets the clock from 64kHz to 640kHz, f _{SLEW} = 320kHz × 47k Ω /R _{TIME} .
40	TON	On-Time Selection Control Input. This four-level input sets the K-factor value (Table 3) used to determine the DH on-time (see the <i>On-Time One-Shot</i> section). GND = 1000kHz, REF = 550kHz, OPEN = 300kHz, VCC = 200kHz.

Table 1. Component Selection for Standard Multiphase Applications (Figure 1)

DESIGNATION	COMPONENT		
Input Voltage Range*	8V to 24V		
VID Output Voltage (D5-D0)	1.308V (D5–D0 = 011001)		
Boot Voltage (B0-B2)	1.004V (B2 = OPEN, B1 = V _{CC} , B0 = GND)		
Suspend Voltage (S0-S2)	0.748V (S2 = OPEN, S1 = V _{CC} , S0 = GND)		
Deep-Sleep Offset Voltage (POS, NEG)	-50mV		
Maximum Load Current	40A		
Inductor (per phase)	0.6µH Sumida CDEP134H-0R6, Panasonic ETQP6F0R6BFA, or BI Technologies HM73-30R60		
Switching Frequency	300kHz (TON = float)		
High-Side MOSFET (N _H , per phase)	International Rectifier (2) IRF7811W or Siliconix (2) Si4892DY		

Low-Side MOSFET (N _L , per phase)	International Rectifier (2) IRF7822, Fairchild (3) FDS7764A, or Siliconix (2) Si4860DY
Input Capacitor (C _{IN})	(6) 10µF 25V Taiyo Yuden TMK432BJ106KM or TDK C4532X5R1E106M
Output Capacitor (C _{OUT})	(5) 330µF 2.5V Panasonic EEFUE0E331XR
Current-Sense Resistor (RSENSE, per phase)	1.5mΩ Panasonic ERJM1WTJ1M5U
Schottky Diodes (D1, D2, D3)	Central Semiconductor CMPSH-3

DESIGNATION

^{*}Input voltages less than 8V requires additional input capacitance.

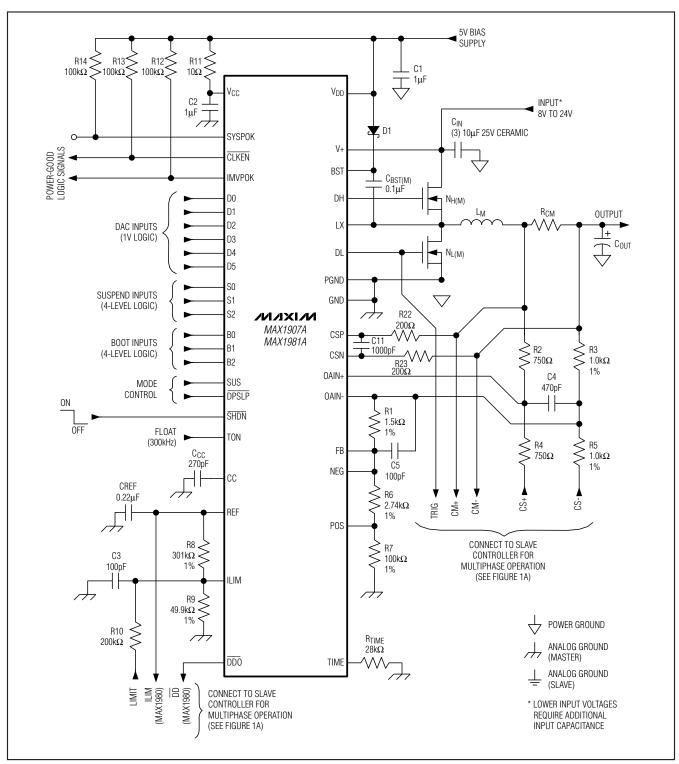


Figure 1. Standard Multiphase Application Circuit

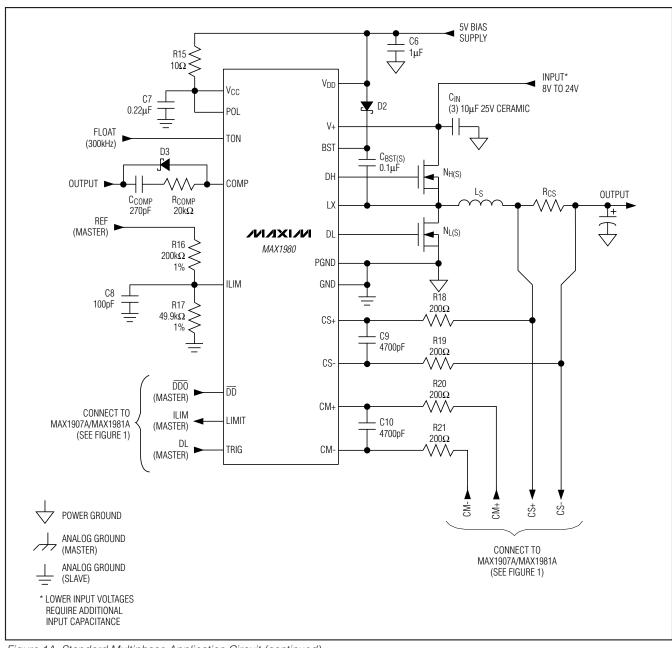


Figure 1A. Standard Multiphase Application Circuit (continued)

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Table 2. Component Suppliers

SUPPLIER	PHONE	WEBSITE
BI Technologies	714-447-2345 (USA)	www.bitechnologies.com
Central Semiconductor	631-435-1110 (USA)	www.centralsemi.com
Coilcraft	800-322-2645 (USA)	www.coilcraft.com
Coiltronics	561-752-5000 (USA)	www.coiltronics.com
Fairchild Semiconductor	888-522-5372 (USA)	www.fairchildsemi.com
International Rectifier	310-322-3331 (USA)	www.irf.com
Kemet	408-986-0424 (USA)	www.kemet.com
Panasonic	847-468-5624 (USA)	www.panasonic.com
Sanyo	408-749-9714 (USA) 65-281-3226 (Singapore)	www.secc.co.jp
Siliconix (Vishay)	203-268-6261 (USA)	www.vishay.com
Sumida	408-982-9660 (USA)	www.sumida.com
Taiyo Yuden	408-573-4150 (USA) 03-3667-3408 (Japan)	www.t-yuden.com
TDK	847-803-6100 (USA) 81-3-5201-7241 (Japan)	www.component.tdk.com
Toko	858-675-8013 (USA)	www.tokoam.com

Detailed Description

5V Bias Supply (VCC and VDD)

The MAX1907A/MAX1981A require an external 5V bias supply in addition to the battery. Typically, this 5V bias supply is the notebook's 95% efficient 5V system supply. Keeping the bias supply external to the IC improves efficiency and eliminates the cost associated with the 5V linear regulator that would otherwise be needed to supply the PWM circuit and gate drivers. If stand-alone capability is needed, the 5V supply can be generated with an external linear regulator.

The 5V bias supply must provide V_{CC} (PWM controller) and V_{DD} (gate-drive power), so the maximum current drawn is:

$$I_{BIAS} = I_{CC} + f_{SW} (Q_{G(LOW)} + Q_{G(HIGH)})$$

= 10mA to 60mA (typ)

where I_{CC} is 1.3mA (typ), fs_W is the switching frequency, and Q_{G(LOW)} and Q_{G(HIGH)} are the MOSFET data sheet's total, gate-charge specification limits at V_{GS} = 5V

V+ and V_{DD} can be tied together if the input power source is a fixed 4.5V to 5.5V supply. If the 5V bias supply is powered up prior to the battery supply, the enable signal (SHDN going from low to high) must be delayed until the battery voltage is present to ensure startup.

Free-Running, Constant On-Time PWM Controller with Input Feed-Forward

The Quick-PWM control architecture is a pseudo-fixed-frequency, constant-on-time, current-mode regulator with voltage feed-forward (Figure 2). This architecture relies on the output filter capacitor's ESR to act as the current-sense resistor, so the output ripple voltage provides the PWM ramp signal. The control algorithm is simple: the high-side switch on-time is determined solely by a one-shot whose period is inversely proportional to input voltage and directly proportional to output voltage. Another one-shot sets a minimum off-time (400ns, typ). The on-time one-shot is triggered if the error comparator is low, the low-side switch current is below the current-limit threshold, and the minimum off-time one-shot has timed out.

On-Time One-Shot (TON)

The heart of the PWM core is the one-shot that sets the high-side switch on-time. This fast, low-jitter, adjustable one-shot includes circuitry that varies the on-time in response to battery and output voltage. The high-side switch on-time is inversely proportional to the battery voltage as measured by the V+ input, and proportional to the output voltage:

$$t_{ON} = K(V_{FB} + 0.075V) / V_{IN}$$

where K is set by the TON pin-strap connection (Table 3) and 0.075V is an approximation to accommodate the

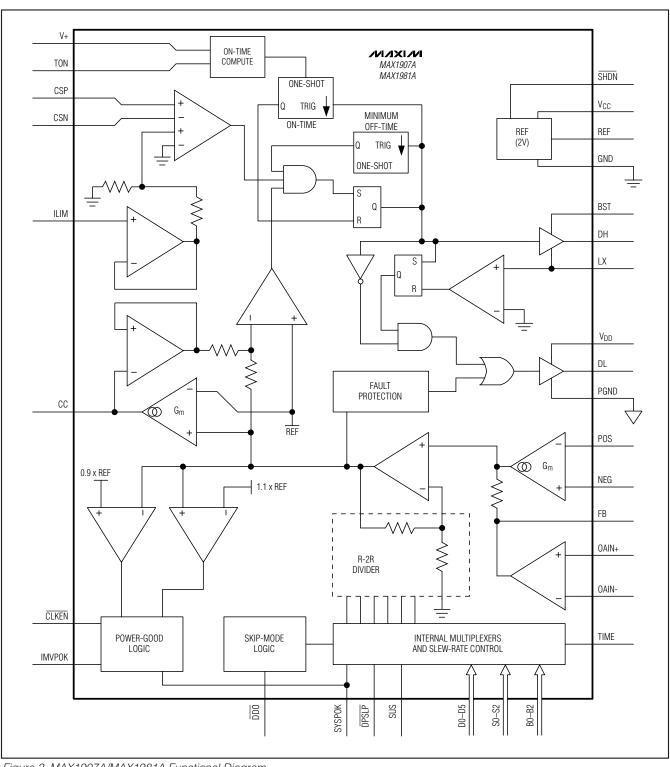


Figure 2. MAX1907A/MAX1981A Functional Diagram

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expected drop across the low-side MOSFET switch. This algorithm results in a nearly constant switching frequency despite the lack of a fixed-frequency clock generator. The benefits of a constant switching frequency are twofold: 1) the frequency can be selected to avoid noise-sensitive regions such as the 455kHz IF band; 2) the inductor ripple-current operating point remains relatively constant, resulting in easy design methodology and predictable output voltage ripple.

The on-time one-shot has good accuracy at the operating points specified in the *Electrical Characteristics* (±10% at 200kHz and 300kHz, ±12% at 550kHz and 1000kHz). On-times at operating points far removed from the conditions specified in the *Electrical Characteristics* can vary over a wider range. For example, the 1000kHz setting will typically run about 10% slower with inputs much greater than 5V due to the very short on-times required.

On-times translate only roughly to switching frequencies. The on-times guaranteed in the *Electrical Characteristics* are influenced by switching delays in the external high-side MOSFET. Resistive losses, including the inductor, both MOSFETs, output capacitor ESR, and PC board copper losses in the output and ground tend to raise the switching frequency at higher output currents. Also, the dead-time effect increases the effective on-time, reducing the switching frequency. It occurs only in PWM mode (SUS = low, DPSLP = low) and during dynamic output voltage transitions when the inductor current reverses at light or negative load currents. With reversed inductor current, the inductor's EMF causes LX to go high earlier than normal, extending the on-time by a period equal to the DH-rising dead time.

For loads above the critical conduction point, where the dead-time effect is no longer a factor, the actual switching frequency is:

$$f_{SW} = \frac{\left(V_{OUT} + V_{DROP1}\right)}{t_{ON}\left(V_{IN} + V_{DROP1} - V_{DROP2}\right)}$$

where V_{DROP1} is the sum of the parasitic voltage drops in the inductor discharge path, including synchronous rectifier, inductor, and PC board resistances; V_{DROP2} is the sum of the parasitic voltage drops in the inductor charge path, including high-side switch, inductor, and PC board resistances; and t_{ON} is the on-time calculated by the MAX1907A/MAX1981A.

Table 3. Approximate K-Factor Errors

TON CONNECTION	FREQUENCY SETTING (kHz)	K-FACTOR (μs)	MAX K-FACTOR ERROR (%)
Vcc	200	5	±10
Float	300	3.3	±10
REF	550	1.8	±12.5
GND	1000	1.0	±12.5

Integrator Amplifiers/ Output Voltage Offsets

Two transconductance amplifiers provide a fine adjustment to the output regulation point (Figure 2). One amplifier forces the DC average of the feedback voltage to equal the VID DAC setting. The second amplifier is used to create small positive or negative offsets to the feedback voltage, using the POS and NEG pins.

The feedback amplifier integrates the feedback voltage, allowing accurate DC output voltage regulation regardless of the output ripple voltage. The feedback amplifier has the ability to shift the output voltage by ±8%. The differential input voltage range is at least ±80mV total, including DC offset and AC ripple. The integration time constant can be set easily with one capacitor at the CC pin. Use a capacitor value of 47pF to 1000pF (270pF, typ).

The POS/NEG amplifier is used to add small offsets to the VID DAC setting in deep-sleep mode (\overline{DPSLP} = low). The offset amplifier is summed directly with the feedback voltage, making the offset gain independent of the DAC code. This amplifier has the ability to offset the output by ± 200 mV. To create an output offset, bias POS and NEG to a voltage (typically V_{OUT} or REF) within their 0 to 2V common-mode range, and offset them from one another with a resistive divider (Figure 1). If V_{POS} is higher than V_{NEG}, then the output is shifted in the positive direction. If V_{NEG} is higher than V_{POS}, then the output is shifted in the negative direction. The output offset equals the voltage difference from POS to NEG.

Forced-PWM Operation (Normal Mode)

During normal mode, when the CPU is actively running (SUS = low and \overline{DPSLP} = high), the MAX1907A/MAX1981A operates with the low-noise, forced-PWM control scheme. Forced-PWM operation disables the zero-crossing comparator, forcing the low-side gate-drive waveform to constantly be the complement of the high-side gate-drive waveform. The benefit of forced-PWM mode is to keep the switching frequency fairly constant.

Forced-PWM operation comes at a cost: the no-load 5V bias supply current remains between 10mA to 40mA, depending on the external MOSFETs and switching frequency. To maintain high efficiency under light load conditions, the MAX1907A/MAX1981A automatically switches to the low-power pulse skipping control scheme after entering suspend or deep-sleep mode.

During all output voltage and mode transitions, the MAX1907A/MAX1981A uses forced-PWM operation in order to ensure fast, accurate transitions. Since forced-PWM operation disables the zero-crossing comparator, the inductor current reverses under light loads, quickly discharging the output capacitors. The controller maintains forced-PWM operation for 30 clock cycles (set by RTIME) after the controller sets the last DAC code value to guarantee the output voltage settles properly before entering pulse-skipping operation.

Low-Power Pulse Skipping

During deep-sleep mode (DPSLP = low) or low-power suspend (SUS = high), the MAX1907A/MAX1981A uses an automatic pulse-skipping control scheme.

For deep-sleep mode, when the CPU pulls DPSLP low, the MAX1907A/MAX1981A shifts the output voltage to incorporate the offset voltage set by the POS and NEG inputs. The controller pulls the driver-disable output (DDO) low 32 RTIME clock cycles after DPSLP goes low. Another 30 RTIME clock cycles later, the MAX1907A/MAX1981A enters low-power operation, allowing automatic pulse skipping under light loads. When the CPU drives DPSLP high, the MAX1907A/MAX1981A immediately enters forced-PWM operation, forces DDO high, and eliminates the output offset, slewing the output to the operating voltage set by the D0–D5 inputs. When either DPSLP transition occurs, the MAX1907A/MAX1981A forces IMVPOK high and CLKEN low for 32 RTIME clock cycles.

When entering suspend mode (SUS driven high), the MAX1907A/MAX1981A slews the output down to the suspend output voltage set by SO-S2 inputs. 32 RTIME clock cycles after the slew-rate controller reaches the last DAC code (see the *Output Voltage Transition Timing* section), the driver-disable output (DDO) is asserted low. After another 30 RTIME clock cycles, the MAX1907A/MAX1981A enters low-power operation, allowing pulse skipping under light loads. When the CPU pulls SUS low, the MAX1907A/MAX1981A immediately enters forced-PWM operation, forces DDO high, and slews the output up to the operating voltage set by the D0-D5 inputs. When either SUS transition occurs, the MAX1907A/MAX1981A blanks IMVPOK and CLKEN, preventing IMVPOK from going low and CLKEN from

going high. The blanking remains until the slew-rate controller has reached the last DAC code and 32 RTIME clock pulses have passed.

In multiphase applications, the driver-disable signal is used to force one or more slave regulators into a high-impedance state. When the master's \$\overline{DDO}\$ output is driven low, the slave controller with driver disable (MAX1980) forces its DL (SLAVE) and DH (SLAVE) gate drivers low, effectively disabling the slave controller. Disabling the slave controller for single-phase operation allows the MAX1907A/MAX1981A to enter low-power pulse-skipping operation under low-power conditions, improving light-load efficiency. When \$\overline{DDO}\$ is driven high, the slave controller (MAX1980) enables the drivers, allowing normal forced-PWM operation.

Automatic Pulse-Skipping Switchover

In skip mode (SUS = high, or \overline{DPSLP} = low), an inherent automatic switchover to PFM takes place at light loads (Figure 3). This switchover is effected by a comparator that truncates the low-side switch on-time at the inductor current's zero crossing. The zero-crossing comparator senses the inductor current across the low-side MOSFET. Once V_{LX} - VP_{GND} drops below 4mV (typ), the comparator forces DL low (Figure 2). This mechanism causes the threshold between pulse-skipping PFM and non-skipping PWM operation to coincide with the boundary between continuous and discontinuous inductor-current operation. The load-current level at which PFM/PWM crossover occurs, ILOAD(SKIP), is equal to 1/2 the peak-to-peak ripple current, which is a function of the inductor value (Figure 4). For a battery range of 8V to 24V, this threshold is relatively constant, with only a minor dependence on battery voltage:

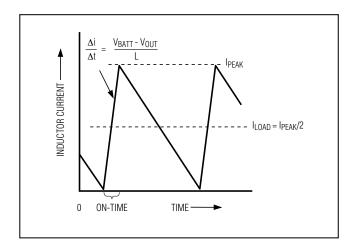
$$I_{LOAD(SKIP)} = \left(\frac{V_{OUT}K}{2L}\right) \left(\frac{V_{BATT} - V_{OUT}}{V_{BATT}}\right)$$

where K is the on-time scale factor (Table 3). For example, in the standard application circuit this becomes:

$$\left(\frac{1.3V \times 3.3\mu s}{2 \times 0.68\mu H}\right) \left(\frac{12.0V - 1.3V}{12.0V}\right) = 2.8A$$

The crossover point occurs at a lower value if a swinging (soft-saturation) inductor is used. The switching waveforms may appear noisy and asynchronous when light loading causes pulse-skipping operation, but this is a normal operating condition that results in high light-load efficiency. Trade-offs in PFM noise vs. light-load efficiency are made by varying the inductor value. Generally, low inductor values produce a broader effi-

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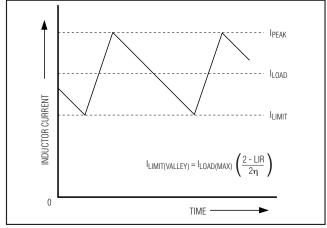


Figure 4. "Valley" Current-Limit Threshold Point

ciency vs. load curve, while higher values result in higher full-load efficiency (assuming that the coil resistance remains fixed) and less output voltage ripple. Penalties for using higher inductor values include larger physical size and degraded load-transient response, especially at low input voltage levels.

Current-Limit Circuit

The current-limit circuit employs a unique "valley" current-sensing algorithm that uses a current-sense resistor between CSP and CSN as the current-sensing element (Figure 1). If the current-sense signal is above the current-limit threshold, the PWM is not allowed to initiate a new cycle (Figure 2). Since only the "valley" current is actively limited, the actual peak current is greater than the current-limit threshold by an amount equal to the inductor ripple current. Therefore, the exact current-limit characteristic and maximum load

capability are a function of the current-sense resistance, inductor value, and battery voltage. When combined with the undervoltage protection circuit, this current-limit method is effective in almost every circumstance.

There is also a negative current limit that prevents excessive reverse inductor currents when VOUT is sinking current. The negative current-limit threshold is set to approximately 120% of the positive current limit, and therefore tracks the positive current limit when ILIM is adjusted.

The current-limit threshold is adjusted with an external resistor-divider at ILIM. The current-limit threshold voltage adjustment range is from 10mV to 150mV. In the adjustable mode, the current-limit threshold voltage is precisely 1/10th the voltage seen at ILIM. The threshold defaults to 50mV when ILIM is connected to VCC. The logic threshold for switchover to the 50mV default value is approximately VCC - 1V.

Carefully observe the PC board layout guidelines to ensure that noise and DC errors do not corrupt the current-sense signals seen by LX and GND. Place the IC close to the low-side MOSFET with short, direct traces, making a Kelvin sense connection to the source and drain terminals.

MOSFET Gate Drivers (DH, DL)

The DH and DL drivers are optimized for driving moderately sized high-side and larger low-side power MOSFETs. This is consistent with the low duty factor seen in the notebook CPU environment, where a large VIN - VOLIT differential exists. An adaptive dead-time circuit monitors the DL output and prevents the highside FET from turning on until DL is fully off. There must be a low-resistance, low-inductance path from the DL driver to the MOSFET gate in order for the adaptive dead-time circuit to work properly. Otherwise, the sense circuitry in the MAX1907A/MAX1981A will interpret the MOSFET gate as "off" while there is actually charge still left on the gate. Use very short, wide traces (50 to 100 mils wide if the MOSFET is 1in from the device). The dead time at the other edge (DH turning off) is determined by a fixed 35ns internal delay.

The internal pulldown transistor that drives DL low is robust, with a 0.5Ω (typ) on-resistance. This helps prevent DL from being pulled up due to capacitive coupling from the drain to the gate of the low-side MOSFET when LX switches from ground to VIN. Applications with high input voltages and long inductive traces may require additional gate-to-source capacitance to ensure fast-rising LX edges do not pullup the DL gate driver, causing shoot-through currents. The capacitive cou-

pling between LX and DL created by the MOSFETs' gate-to-drain capacitance (CRSS), gate-to-source (CISS-CRSS), and additional board parasitics should not exceed the following minimum threshold voltage:

$$V_{GS(TH)} < V_{IN} \left(\frac{C_{RSS}}{C_{ISS}} \right)$$

Lot-to-lot variation of the threshold voltage may cause problems in marginal designs. Typically, adding 4700pF between DL and power ground close to the low-side MOSFETs greatly reduces coupling. Due should not exceed 22nF of total gate capacitance to prevent excessive turn-off delays. Alternatively, adding a resistor less than 5Ω in series with BST may remedy the problem by increasing the turn-on time of the high-side MOSFET without degrading the turn-off time (Figure 5).

Voltage Positioning Amplifier

The MAX1907A/MAX1981A includes a dedicated operational amplifier for adding gain to the voltage positioning sense path. The voltage positioning gain allows the use of low-value, current-sense resistors in order to minimize power dissipation. This 3MHz gain-bandwidth amplifier was designed with low offset voltage (70µV, typ) to meet the IMVP-IV output accuracy requirements.

The inverting (OAIN-) and noninverting (OAIN+) inputs are used to differentially sense the voltage across the voltage-positioning sense resistor. The op amp's output is internally connected to the regulator's feedback input (FB). The op amp should be configured as a noninverting, differential amplifier as shown in Figure 1. The voltage positioning slope is set by properly selecting the feedback resistor connected from FB to OAIN- (see the Setting Voltage Positioning section). For applications using a slave controller, additional differential input resistors (summing configuration) should be connected to the slave's voltage-positioning sense resistor (Figure 1). Summing together both the master and slave current-sense signals ensures that the voltage-positioning slope will remain constant when the slave controller is disabled.

In applications that do not require voltage-positioning gain, the amplifier can be disabled by connecting the OAIN- pin directly to V_{CC} . The disabled amplifier's output becomes high-impedance, guaranteeing that the unused amplifier will not corrupt the FB input signal. The logic threshold to disable the op amp is approximately V_{CC} - 1V.

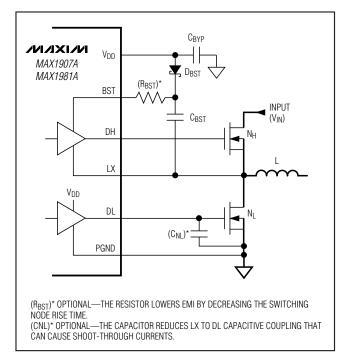


Figure 5. High-Side Gate-Driver Boost Circuitry

Power-On Reset

Power-on reset (POR) occurs when V_{CC} rises above approximately 2V, resetting the fault latch and preparing the PWM for operation. V_{CC} undervoltage lockout (UVLO) circuitry inhibits switching, and forces the DL gate driver high (to enforce output overvoltage protection). When V_{CC} rises above 4.25V, the DAC inputs are sampled and the output voltage begins to slew to the boot voltage (Table 7).

For automatic startup, the battery voltage should be present before V_{CC}. If the MAX1907A/MAX1981A attempts to bring the output into regulation without the battery voltage present, the fault latch will trip. The SHDN pin can be toggled to reset the fault latch.

Input Undervoltage Lockout

During start-up, the V_{CC} UVLO circuitry forces the DL gate driver high and the DH gate driver low, inhibiting switching until an adequate supply voltage is reached. Once V_{CC} rises above 4.25V, valid transitions detected at the trigger input initiate a corresponding on-time pulse (see the *On-Time One-Shot* section).

If the V_{CC} voltage drops below 4.25V, it is assumed that there is not enough supply voltage to make valid decisions. To protect the output from overvoltage faults, DL is forced high in this mode to force the output to ground.

This results in large negative inductor current and possibly small negative output voltages. If $V_{\rm CC}$ is likely to drop in this fashion, the output can be clamped with a Schottky diode to PGND to reduce the negative excursion.

Shutdown

When SHDN or SYSPOK goes low, the MAX1907A/MAX1981A enters low-power shutdown mode. IMVPOK is pulled low and CLKEN is driven high immediately. The output voltage ramps down to 0 in 16mV steps at the clock rate set by RTIME. When the DAC reaches the 0 setting, DL goes high, DH goes low, the reference is turned off, and the supply current drops to about 0.1µA. When SYSPOK activates the shutdown sequence, the controller also sets the fault latch to prevent the controller from restarting. To clear the fault latch and reactivate the MAX1907A/MAX1981A, toggle SHDN or cycle VCC power below 1V.

When SHDN goes high, the reference powers up, and after the reference UVLO is passed, the DAC target is evaluated and switching begins. The slew-rate controller ramps up from 0 in 16mV steps to the currently selected boot code value (see the *Power-Up Sequence* section). There is no traditional soft-start (variable current limit) circuitry, so full output current is available immediately. SYSPOK becomes high-impedance after the reference exceeds its UVLO threshold.

DAC Inputs (D0-D5)

During normal operation (SUS = low), the digital-to-analog converter (DAC) programs the output voltage using the D0–D5 inputs. D0–D5 are low-voltage (1V) logic inputs, designed to interface directly with the IMVP-IV CPU. Do not leave D0–D5 unconnected. D0–D5 can be changed while the MAX1907A/MAX1981A is active, initiating a transition to a new output voltage level. Change D0–D5 together, avoiding greater than 1µs skew between bits. Otherwise, incorrect DAC readings may cause a partial transition to the wrong voltage level followed by the intended transition to the correct voltage level, lengthening the overall transition time. The available DAC codes and resulting output voltages (Table 5) are compatible with IMVP-IV specification.

Four-Level Logic Inputs

TON, B0–B2, and S0–S2 are four-level logic inputs. These inputs help expand the functionality of the controller without adding an excessive number of pins. The four-level inputs are intended to be static inputs. When left open, an internal resistive divider sets the input voltage to approximately 3.5V. Therefore, connect the four-level logic inputs directly to $V_{\rm CC}$, REF, or GND when selecting one of the other logic levels. See the *Electrical Characteristics* for exact logic-level voltages.

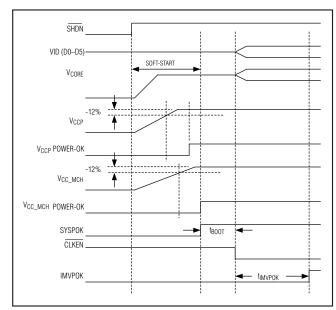


Figure 6. Power-Up Sequence Timing Diagram

Power-Up Sequence

The MAX1907A/MAX1981A is enabled when SHDN is driven high (Figure 6). First, the reference powers up. Once the reference exceeds its undervoltage lockout threshold, the PWM regulator becomes active. The slew-rate controller ramps up the output voltage in 16mV increments to the selected boot code value (B0–B2, Table 7). The ramp rate is set with the RTIME resistor (see the *Output Voltage Transition Timing* section).

SYSPOK serves as the combined power-good input for VCCP and VCC_MCH. Once these supplies are within ±10% of their output voltage, their power good outputs become high-impedance, allowing SYSPOK to be pulled high. Approximately 50µs after the MAX1907A/MAX1981A detects a logic high voltage on SYSPOK and the FB voltage reaches the target voltage set by B0-B2, the controller pulls CLKEN low and slews the output to the proper operating voltage (see Table 4).

When CLKEN goes low, the MAX1907A/MAX1981A keeps IMVPOK low for an additional 3ms (min), guaranteeing that the CPU has time to start properly. If the MAX1907A/MAX1981A does not detect a fault, then IMVPOK will be pulled high once the 3ms timer expires.

Table 4. Operating Mode Truth Table

SHDN	SYSPOK	sus	DPSLP	DDO	OUTPUT VOLTAGE	OPERATING MODE
0	х	х	х	0	GND	Low-Power Shutdown Mode. DL is forced high (V _{DD}), DH is forced low (LX), and the PWM controller is disabled. The supply current drops to 0.1µA (typ).
1	0	0	×	1	B0-B2 (No offset)	Power-Up Mode. When enabled, the MAX1907A/MAX1981A softly ramps up the output voltage to the selected boot voltage (B0–B2, Table 7). The controller remains at the boot voltage until SYSPOK is driven high (see the <i>Power-Up Sequence</i> section).
1	1	0	1	1	D0-D5 (No offset)	Normal Operation. The no-load output voltage is determined by the selected VID DAC code (D0-D5, Table 5).
1	1	0	0	0	D0-D5 (Plus offset)	Deep-Sleep Mode. The no-load output voltage is determined by the selected VID DAC code (D0–D5, Table 5) plus the offset voltage set by POS and NEG. Operation with automatic PWM/PFM switchover for pulse skipping under light loads.
1	х	1	х	0	S0–S2 (No offset)	Suspend Mode. The no-load output voltage is determined by the selected suspend code (S0–S2, Table 6). Operation with automatic PWM/PFM switchover for pulse skipping under light loads.
1	0	Х	Х	0	GND	Fault Mode. The fault latch has been set by either UVP, OVP (MAX1907A only), thermal shutdown, or a falling edge on SYSPOK. The controller will remain in FAULT mode until VCC power is cycled or SHDN toggled.

Table 5. Output Voltage VID DAC Codes (SUS = Low)

D5	D4	D3	D2	D1	D0	OUTPUT VOLTAGE (V)
0	0	0	0	0	0	1.708
0	0	0	0	0	1	1.692
0	0	0	0	1	0	1.676
0	0	0	0	1	1	1.660
0	0	0	1	0	0	1.644
0	0	0	1	0	1	1.628
0	0	0	1	1	0	1.612
0	0	0	1	1	1	1.596
0	0	1	0	0	0	1.580
0	0	1	0	0	1	1.564
0	0	1	0	1	0	1.548
0	0	1	0	1	1	1.532
0	0	1	1	0	0	1.516
0	0	1	1	0	1	1.500
0	0	1	1	1	0	1.484
0	0	1	1	1	1	1.468
0	1	0	0	0	0	1.452
0	1	0	0	0	1	1.436
0	1	0	0	1	0	1.420
0	1	0	0	1	1	1.404
0	1	0	1	0	0	1.388
0	1	0	1	0	1	1.372
0	1	0	1	1	0	1.356
0	1	0	1	1	1	1.340
0	1	1	0	0	0	1.324
0	1	1	0	0	1	1.308
0	1	1	0	1	0	1.292
0	1	1	0	1	1	1.276
0	1	1	1	0	0	1.260
0	1	1	1	0	1	1.244
0	1	1	1	1	0	1.228
0	1	1	1	1	1	1.212

D5	D4	D3	D2	D1	D0	OUTPUT VOLTAGE (V)
1	0	0	0	0	0	1.196
1	0	0	0	0	1	1.180
1	0	0	0	1	0	1.164
1	0	0	0	1	1	1.148
1	0	0	1	0	0	1.132
1	0	0	1	0	1	1.116
1	0	0	1	1	0	1.100
1	0	0	1	1	1	1.084
1	0	1	0	0	0	1.068
1	0	1	0	0	1	1.052
1	0	1	0	1	0	1.036
1	0	1	0	1	1	1.020
1	0	1	1	0	0	1.004
1	0	1	1	0	1	0.988
1	0	1	1	1	0	0.972
1	0	1	1	1	1	0.956
1	1	0	0	0	0	0.940
1	1	0	0	0	1	0.924
1	1	0	0	1	0	0.908
1	1	0	0	1	1	0.892
1	1	0	1	0	0	0.876
1	1	0	1	0	1	0.860
1	1	0	1	1	0	0.844
1	1	0	1	1	1	0.828
1	1	1	0	0	0	0.812
1	1	1	0	0	1	0.796
1	1	1	0	1	0	0.780
1	1	1	0	1	1	0.764
1	1	1	1	0	0	0.748
1	1	1	1	0	1	0.732
1	1	1	1	1	0	0.716
1	1	1	1	1	1	0.700

Table 6. Suspend Mode DAC Codes (SUS = High)

S2	S1	S0	OUTPUT VOLTAGE (V)
GND	GND	GND	1.452
GND	GND	REF	1.436
GND	GND	OPEN	1.420
GND	GND	Vcc	1.404
GND	REF	GND	1388
GND	REF	REF	1.372
GND	REF	OPEN	1.356
GND	REF	Vcc	1.340
GND	OPEN	GND	1.324
GND	OPEN	REF	1.308
GND	OPEN	OPEN	1.292
GND	OPEN	Vcc	1.276
GND	Vcc	GND	1.260
GND	Vcc	REF	1.244
GND	Vcc	OPEN	1.228
GND	V _{CC}	V _{CC}	1.212
REF	GND	GND	1.196
REF	GND	REF	1.180
REF	GND	OPEN	1.164
REF	GND	Vcc	1.148
REF	REF	GND	1.132
REF	REF	REF	1.116
REF	REF	OPEN	1.100
REF	REF	Vcc	1.084
REF	OPEN	GND	1.068
REF	OPEN	REF	1.052
REF	OPEN	OPEN	1.036
REF	OPEN	Vcc	1.020
REF	Vcc	GND	1.004
REF	Vcc	REF	0.988
REF	Vcc	OPEN	0.972
REF	Vcc	VCC	0.956

S2	S1	S0	OUTPUT VOLTAGE (V)
OPEN	GND	GND	0.940
OPEN	GND	REF	0.924
OPEN	GND	OPEN	0.908
OPEN	GND	Vcc	0.892
OPEN	REF	GND	0.876
OPEN	REF	REF	0.860
OPEN	REF	OPEN	0.844
OPEN	REF	Vcc	0.828
OPEN	OPEN	GND	0.812
OPEN	OPEN	REF	0.796
OPEN	OPEN	OPEN	0.780
OPEN	OPEN	Vcc	0.764
OPEN	Vcc	GND	0.748
OPEN	Vcc	REF	0.732
OPEN	Vcc	OPEN	0.716
OPEN	Vcc	Vcc	0.700
V _{CC}	GND	GND	0.684
Vcc	GND	REF	0.668
Vcc	GND	OPEN	0.652
Vcc	GND	Vcc	0.636
Vcc	REF	GND	0.620
Vcc	REF	REF	0.604
Vcc	REF	OPEN	0.588
Vcc	REF	Vcc	0.572
Vcc	OPEN	GND	0.556
V _C C	OPEN	REF	0.540
Vcc	OPEN	OPEN	0.524
Vcc	OPEN	Vcc	0.508
Vcc	Vcc	GND	0.492
Vcc	Vcc	REF	0.476
Vcc	Vcc	OPEN	0.460
Vcc	Vcc	Vcc	0.444

Table 7. Boot-Mode DAC Codes (Power-Up)

B2	B1	В0	OUTPUT VOLTAGE (V)
GND	GND	GND	1.708
GND	GND	REF	1.692
GND	GND	OPEN	1.676
GND	GND	Vcc	1.660
GND	REF	GND	1.644
GND	REF	REF	1.628
GND	REF	OPEN	1.612
GND	REF	Vcc	1.596
GND	OPEN	GND	1.580
GND	OPEN	REF	1.564
GND	OPEN	OPEN	1.548
GND	OPEN	Vcc	1.532
GND	Vcc	GND	1.516
GND	Vcc	REF	1.500
GND	Vcc	OPEN	1.484
GND	Vcc	Vcc	1.468
REF	GND	GND	1.452
REF	GND	REF	1.436
REF	GND	OPEN	1.420
REF	GND	Vcc	1.404
REF	REF	GND	1.388
REF	REF	REF	1.372
REF	REF	OPEN	1.356
REF	REF	Vcc	1.340
REF	OPEN	GND	1.324
REF	OPEN	REF	1.308
REF	OPEN	OPEN	1.292
REF	OPEN	Vcc	1.276
REF	Vcc	GND	1.260
REF	Vcc	REF	1.244
REF	Vcc	OPEN	1.228
REF	V _{CC}	V _{CC}	1.212

B2	B1	В0	OUTPUT VOLTAGE (V)
OPEN	GND	GND	1.196
OPEN	GND	REF	1.180
OPEN	GND	OPEN	1.164
OPEN	GND	Vcc	1.148
OPEN	REF	GND	1.132
OPEN	REF	REF	1.116
OPEN	REF	OPEN	1.100
OPEN	REF	Vcc	1.084
OPEN	OPEN	GND	1.068
OPEN	OPEN	REF	1.052
OPEN	OPEN	OPEN	1.036
OPEN	OPEN	V _{CC}	1.020
OPEN	Vcc	GND	1.004
OPEN	Vcc	REF	0.988
OPEN	VCC	OPEN	0.972
OPEN	Vcc	Vcc	0.956
Vcc	GND	GND	0.940
Vcc	GND	REF	0.924
Vcc	GND	OPEN	0.908
Vcc	GND	Vcc	0.892
Vcc	REF	GND	0.876
Vcc	REF	REF	0.860
Vcc	REF	OPEN	0.844
Vcc	REF	Vcc	0.828
Vcc	OPEN	GND	0.812
Vcc	OPEN	REF	0.796
Vcc	OPEN	OPEN	0.780
Vcc	OPEN	Vcc	0.764
V _{CC}	V _{CC}	GND	0.748
Vcc	Vcc	REF	0.732
Vcc	Vcc	OPEN	0.716
Vcc	Vcc	Vcc	0.700

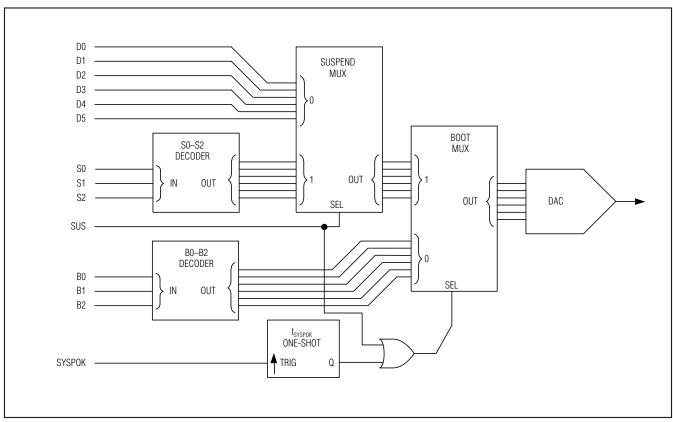


Figure 7. Internal Multiplexers Functional Diagram

Internal Multiplexers

The MAX1907A/MAX1981A has two unique internal DAC input multiplexers (muxes) that can select one of three different DAC code settings for different processor states. On startup, the controller selects the DAC code from the B0–B2 input decoder. Once SYSPOK goes high and the MAX1907A/MAX1981A properly regulates to the boot voltage, a second multiplexer selects the DAC code from either D0–D5 (SUS = low) or S0–S2 (SUS = high), depending on the SUS state (Figure 7).

Suspend Mode

When the processor enters low-power suspend mode, the system uses a lower supply voltage to reduce power consumption. The MAX1907A/MAX1981A include independent suspend-mode output voltage codes set by the four-level inputs S0–S2. When the CPU suspends operation, SUS is driven high, overriding the 6-bit VID DAC code set by D0–D5. The master controller slews the output to the selected suspend-mode voltage. During the transition, the MAX1907A/MAX1981A asserts forced-PWM operation until 62 RTIME clock cycles after the slew-rate controller reaches the suspend-mode voltage.

When SUS is low, the output voltage is dynamically controlled by the 6-bit VID DAC inputs (D0–D5).

Output Voltage Transition Timing

The MAX1907A/MAX1981A is designed to perform mode transitions in a controlled manner, automatically minimizing input surge currents. This feature allows the circuit designer to achieve nearly ideal transitions, guaranteeing just-in-time arrival at the new output voltage level with the lowest possible peak currents for a given output capacitance. This makes the IC ideal for IMVP-IV CPUs.

At the beginning of an output voltage transition, the MAX1907A/MAX1981A blanks the IMVPOK and CLKEN outputs, preventing them from changing states. IMVPOK and CLKEN remain blanked during the transition and is re-enabled 32 clock cycles after the slew-rate controller has set the final DAC code value. The slew-rate clock frequency (set by resistor R_{TIME}) must be set fast enough to ensure that the transition is completed within the maximum allotted time.

The slew-rate controller transitions the output voltage in 16mV increments during power-up, soft-shutdown, and suspend-mode transitions. The total time for a transition depends on R_{TIME}, the voltage difference, and the

accuracy of the MAX1907A/MAX1981As' slew-rate clock, and is not dependent on the total output capacitance. The greater the output capacitance, the higher the surge current required for the transition. The MAX1907A/MAX1981A automatically control the current to the minimum level required to complete the transition in the calculated time, as long as the surge current is less than the current limit set by ILIM. The transition time is given by:

$$\begin{split} t_{SLEW} &\approx \frac{1}{f_{SLEW}} \left(\frac{V_{NEW} - V_{OLD}}{16 \text{mV}} \right) \text{for } V_{OUT} \text{ rising} \\ t_{SLEW} &\approx \frac{1}{f_{SLEW}} \left[\left(\frac{V_{OLD} - V_{NEW}}{16 \text{mV}} \right) + 2 \right] \text{for } V_{OUT} \text{ falling} \end{split}$$

where f_{SLEW} = $320 \text{kHz} \times 47 \text{k}\Omega$ / R_{TIME}, V_{OLD} is the original DAC setting, and V_{NEW} is the new DAC setting. The additional 2 clock cycles on the falling edge time are due to internal synchronization delays. See Time Frequency Accuracy in the *Electrical Characteristics* for f_{SLEW} accuracy.

The practical range of R_{TIME} is $23.5k\Omega$ to $235k\Omega$ corresponding to $1.6\mu s$ to $15.6\mu s$ per 16mV step. Although the DAC takes discrete 16mV steps, the output filter makes the transitions relatively smooth. The average inductor current required to make an output voltage transition is:

 $I_L \cong C_{OUT} \times 16 \text{mV} \times \text{fSLEW}$

Output Overvoltage Protection (MAX1907A Only)

The overvoltage protection (OVP) circuit is designed to protect the CPU against a shorted high-side MOSFET by drawing high current and blowing the battery fuse. The output voltage is continuously monitored for overvoltage. If the actual output voltage exceeds the set output voltage by more than 13% (min), OVP is triggered and the circuit shuts down. IMVPOK is pulled low and CLKEN is driven high immediately. The DL low-side gate-driver output is then latched high until SHDN is toggled or VCC power is cycled below 1V. This action turns on the synchronous-rectifier MOSFET with 100% duty and, in turn, rapidly discharges the output filter capacitor and forces the output to ground. If the condition that caused the overvoltage (such as a shorted high-side MOSFET) persists, the battery fuse will blow.

OVP can be defeated through the NO FAULT test mode (see the *NO FAULT Test Mode* section).

Output Undervoltage Shutdown

The output undervoltage protection (UVP) function is similar to foldback current limiting, but employs a timer rather than a variable current limit. If the MAX1907A/MAX1981A output voltage is under 70% of the nominal value, the PWM is latched off and won't restart until $\overline{\rm SHDN}$ is toggled or VCC power is cycled below 1V. UVP is ignored during output voltage transitions and remains blanked for an additional 32 clock cycles after the controller reaches the final DAC code value.

UVP can be defeated through the NO FAULT test mode (see the *NO FAULT Test Mode* section).

Thermal Fault Protection

The MAX1907A/MAX1981A features a thermal fault-protection circuit. When the junction temperature rises above 160°C, a thermal sensor activates the fault logic, forces the DL low-side gate-driver high, and pulls the DH high-side gate-driver low. This quickly discharges the output capacitors, tripping the master controller's UVLO protection. Toggle SHDN or cycle VCC power below 1V to reactivate the controller after the junction temperature cools by 15°C.

NO FAULT Test Mode

The OVP and UVP protection features can complicate the process of debugging prototype breadboards since there are (at most) a few milliseconds in which to determine what went wrong. Therefore, a test mode is provided to disable the OVP, UVP, and thermal shutdown features, and clear the fault latch if it has been set. The NO FAULT test mode is entered by forcing 12V to 15V on SHDN.

Design Procedure

Firmly establish the input voltage range and maximum load current before choosing a switching frequency and inductor operating point (ripple-current ratio). The primary design trade-off lies in choosing a good switching frequency and inductor operating point, and the following four factors dictate the rest of the design:

Input Voltage Range. The maximum value ($V_{IN(MAX)}$) must accommodate the worst-case, high-AC-adapter voltage. The minimum value ($V_{IN(MIN)}$) must account for the lowest input voltage after drops due to connectors, fuses, and battery-selector switches. If there is a choice at all, lower input voltages result in better efficiency.

Maximum Load Current. There are two values to consider. The peak load current (ILOAD(MAX)) determines

the instantaneous component stresses and filtering requirements, and thus drives output capacitor selection, inductor saturation rating, and the design of the current-limit circuit. The continuous load current (ILOAD) determines the thermal stresses and thus drives the selection of input capacitors, MOSFETs, and other critical heat-contributing components. Modern notebook CPUs generally exhibit $I_{LOAD} = I_{LOAD(MAX)} \times 80\%$.

For multi-phase systems, each phase supports a fraction of the load, depending on the current balancing. When properly balanced, the load current is evenly distributed among each phase:

$$I_{LOAD(SLAVE)} = I_{LOAD(MASTER)} = \frac{I_{LOAD}}{\eta}$$

where η is the number of phases.

Switching Frequency. This choice determines the basic trade-off between size and efficiency. The optimal frequency is largely a function of maximum input voltage, due to MOSFET switching losses that are proportional to frequency and ${\rm V_{IN}}^2$. The optimum frequency is also a moving target, due to rapid improvements in MOSFET technology that are making higher frequencies more practical.

Setting Slave On-Time. The constant on-time control algorithm in the master results in a nearly constant switching frequency despite the lack of a fixed-frequency clock generator. In the slave, the high-side switch on-time is inversely proportional to V+, and directly proportional to the compensation voltage (VCOMP):

$$t_{ON} = K \left(\frac{V_{COMP}}{V_{IN}} \right)$$

where K set by the TON pin-strap connection (Table 3).

Inductor Operating Point. This choice provides tradeoffs between size vs. efficiency and transient response vs. output noise. Low inductor values provide better transient response and smaller physical size, but also result in lower efficiency and higher output noise due to increased ripple current. The minimum practical inductor value is one that causes the circuit to operate at the edge of critical conduction (where the inductor current just touches zero with every cycle at maximum load). Inductor values lower than this grant no further sizereduction benefit. The optimum operating point is usually found between 20% and 50% ripple current.

Inductor Selection

The switching frequency and operating point (% ripple or LIR) determine the inductor value as follows:

$$L = \frac{V_{OUT} (V_{IN} - V_{OUT}) \eta}{V_{IN} f_{SW} I_{LOAD(MAX)} LIR}$$

where η is the number of phases. Example: η = 2, ILOAD(MAX) = 40A, V_{IN} = 12V, V_{OUT} = 1.3V, f_{SW} = 300kHz, 30% ripple current or LIR = 0.3:

$$L = \frac{1.3V \times (12V - 1.3V) \times 2}{12V \times 300kHz \times 40A \times 0.3} = 0.64\mu H$$

Find a low-loss inductor having the lowest possible DC resistance that fits in the allotted dimensions. Ferrite cores are often the best choice, although powdered iron is inexpensive and can work well at 200kHz. The core must be large enough not to saturate at the peak inductor current (IPEAK):

$$I_{PEAK} = I_{LOAD(MAX)} \left(\frac{2 + LIR}{2\eta} \right)$$

where η is the number of phases.

Transient Response

The inductor ripple current impacts transient-response performance, especially at low VIN - VOUT differentials. Low inductor values allow the inductor current to slew faster, replenishing charge removed from the output filter capacitors by a sudden load step. The amount of output sag is also a function of the maximum duty factor, which can be calculated from the on-time and minimum off-time:

$$V_{SAG} = \frac{L\left(\Delta I_{LOAD(MAX)}\right)^{2} \left[\left(\frac{V_{OUT}K}{V_{IN}}\right) + t_{OFF(MIN)}\right]}{2\eta C_{OUT}V_{OUT} \left[\left(\frac{\left(V_{IN} - V_{OUT}\right)K}{V_{IN}}\right) - t_{OFF(MIN)}\right]}$$

where $t_{OFF(MIN)}$ is the minimum off-time (see the *Electrical Characteristics*), η is the number of phases, and K is from Table 3.

The amount of overshoot due to stored inductor energy can be calculated as:

$$V_{SOAR} \approx \frac{\left(\Delta I_{LOAD(MAX)}\right)^2 L}{2\eta C_{OUT} V_{OUT}}$$

Setting the Current Limit

The minimum current-limit threshold must be great enough to support the maximum load current when the current limit is at the minimum tolerance value. The valley of the inductor current occurs at ILOAD(MAX) minus half the ripple current; therefore:

$$I_{LIMIT(LOW)} > \left(\frac{I_{LOAD(MAX)}}{\eta}\right) - \left(\frac{I_{LOAD(MAX)}LIR}{2\eta}\right)$$

where ILIMIT(LOW) equals the minimum current-limit threshold voltage divided by the current-sense resistor (RSENSE). For the 50mV default setting, the minimum current-limit threshold is 40mV.

Connect ILIM to V_{CC} for a default 50mV current-limit threshold. In adjustable mode, the current-limit threshold is precisely 1/10th the voltage seen at ILIM. For an adjustable threshold, connect a resistive divider from REF to GND with ILIM connected to the center tap. The external 100mV to 2V adjustment range corresponds to a 10mV to 200mV current-limit threshold. When adjusting the current limit, use 1% tolerance resistors and approximately $10\mu A$ divider current to prevent a significant increase of errors in the current-limit tolerance.

In multi-phase applications, set the slave's current-limit threshold above the MAX1907A/MAX1981As' current-limit threshold. This configuration ensures that the slave's current-limit circuitry will not disrupt the current balance required for stable multi-phase regulation. When the MAX1907A/MAX1981A limits the master inductor current, the slave's current-balance circuitry also limits the slave inductor current. However, if the current-balance circuitry fails, the slave controller's current limit provides back-up overcurrent protection.

Output Capacitor Selection

The output filter capacitor must have low enough equivalent series resistance (ESR) to meet output ripple and load-transient requirements, yet have high enough ESR to satisfy stability requirements.

In CPU $V_{\rm CORE}$ converters and other applications where the output is subject to large load transients, the output capacitor's size typically depends on how much ESR is needed to prevent the output from dipping too low under a load transient. Ignoring the sag due to finite capacitance:

$$R_{ESR} \le \frac{V_{STEP}}{\Delta I_{LOAD(MAX)}}$$

MIXIM

In non-CPU applications, the output capacitor's size often depends on how much ESR is needed to maintain an acceptable level of output ripple voltage. The output ripple voltage of a step-down controller equals the total inductor ripple current multiplied by the output capacitor's ESR. When operating multiphase systems out-of-phase, the peak inductor currents of each phase are staggered, resulting in lower output ripple voltage by reducing the total inductor ripple current. For out-of-phase operation, the maximum ESR to meet ripple requirements is:

$$R_{ESR} \leq \frac{V_{RIPPLE}}{\left(\frac{\eta}{L}\right) \left[\left(\frac{V_{IN} - \eta V_{OUT}}{f_{SW}}\right) \left(\frac{V_{OUT}}{V_{IN}}\right) - (\eta - 1)V_{OUT}t_{TRIG}\right]}$$

The previous equation can be rewritten as the singlephase ripple current minus a correction due to the additional phases:

$$R_{ESR} \le \frac{V_{RIPPLE}}{\left[I_{LOAD(MAX)}LIR - \eta(\eta - 1)\left(\frac{V_{OUT}}{L}\right)\left(t_{ON} + t_{TRIG}\right)\right]}$$

where the training is the propagation delay between the multiphase on-times, η is the number of phases, and K is from Table 3. When operating in-phase, the high-side MOSFETs turn on together, so the output capacitors must simultaneously support the combined inductor ripple currents of each phase. For in-phase operation, the maximum ESR to meet ripple requirements is:

$$\begin{split} R_{ESR} & \leq \frac{V_{RIPPLE}}{I_{LOAD(MAX)}LIR} \\ R_{ESR} & \leq \frac{V_{RIPPLE}}{\left(\frac{\eta}{f_{SW}L}\right)\left(\frac{V_{OUT}}{V_{IN}}\right)\left(V_{IN} - V_{OUT}\right)} \end{split}$$

The actual capacitance value required relates to the physical size needed to achieve low ESR, as well as to the chemistry of the capacitor technology. Thus, the capacitor is usually selected by ESR and voltage rating rather than by capacitance value (this is true of tantalums, OS-CONs, and other electrolytics).

When using low-capacity filter capacitors such as ceramic or polymer types, capacitor size is usually determined by the capacity needed to prevent V_{SAG}

and V_{SOAR} from causing problems during load transients. Generally, once enough capacitance is added to meet the overshoot requirement, undershoot at the rising load edge is no longer a problem (see the V_{SAG} and V_{SOAR} equations in the *Transient Response* section).

Output Capacitor Stability ConsiderationsFor Quick-PWM controllers, stability is determined by the value of the ESR zero relative to the switching frequency. The boundary of instability is given by the following equation:

$$f_{\rm ESR} \leq \frac{f_{\rm SW}}{\pi}$$
 where $f_{\rm ESR} = \frac{1}{2\pi R_{\rm ESR} C_{\rm OUT}}$

For a standard 300kHz application, the ESR zero frequency must be well below 95kHz, preferably below 50kHz. Tantalum, Sanyo POSCAP, and Panasonic SP capacitors, in widespread use at the time of publication, have typical ESR zero frequencies below 30kHz. In the standard application used for inductor selection, the ESR needed to support a 30mVp-p ripple is 30mV/(40A \times 0.3) = 2.5m Ω . Five 330µF/2.5V Panasonic SP (type XR) capacitors in parallel provide 2m Ω (max) ESR. Their typical combined ESR results in a zero at 48kHz.

Do not put high-value ceramic capacitors directly across the output without taking precautions to ensure stability. Ceramic capacitors have a high-ESR zero frequency and can cause erratic, unstable operation. However, it is easy to add enough series resistance by placing the capacitors a couple of inches downstream from the junction of the inductor and FB pin.

Unstable operation manifests itself in two related but distinctly different ways: double-pulsing and feedback loop instability. Double-pulsing occurs due to noise on the output or because the ESR is so low that there is not enough voltage ramp in the output voltage signal. This "fools" the error comparator into triggering a new cycle immediately after the minimum off-time period has expired. Double-pulsing is more annoying than harmful, resulting in nothing worse than increased output ripple. However, it can indicate the possible presence of loop instability due to insufficient ESR. Loop instability can result in oscillations at the output after line or load steps. Such perturbations are usually damped, but can cause the output voltage to rise above or fall below the tolerance limits.

The easiest method for checking stability is to apply a very fast zero-to-max load transient and carefully observe the output-voltage-ripple envelope for overshoot and ringing. It can help to simultaneously monitor the inductor current with an AC current probe. Do not allow more than one cycle of ringing after the initial step-response under/overshoot.

Input Capacitor Selection

The input capacitor must meet the ripple current requirement (I_{RMS}) imposed by the switching currents. The multi-phase slave controllers operate out-of-phase, staggering the turn-on times of each phase. This minimizes the input ripple current by dividing the load current among independent phases:

$$I_{RMS} = \left(\frac{I_{LOAD}}{\eta}\right) \left(\frac{\sqrt{\eta V_{OUT} \left(V_{IN} - \eta V_{OUT}\right)}}{V_{IN}}\right)$$

for out-of-phase operation.

When operating the multiphase system in-phase, the high-side MOSFETs turn on simultaneously, so input capacitors must support the combined input ripple currents of each phase:

$$I_{RMS} = I_{LOAD} \left(\frac{\sqrt{V_{OUT}(V_{IN} - V_{OUT})}}{V_{IN}} \right)$$

for in-phase operation.

For most applications, nontantalum chemistries (ceramic, aluminum, or OS-CON) are preferred due to their resistance to inrush surge currents typical of systems with a mechanical switch or connector in series with the input. If the MAX1907A/MAX1981A are operated as the second stage of a two-stage power-conversion system, tantalum input capacitors are acceptable. In either configuration, choose an input capacitor that exhibits less than +10°C temperature rise at the RMS input current for optimal circuit longevity.

Power MOSFET Selection

Most of the following MOSFET guidelines focus on the challenge of obtaining high load-current capability when using high-voltage (>20V) AC adapters. Low-current applications usually require less attention.

The high-side MOSFET (N_H) must be able to dissipate the resistive losses plus the switching losses at both $V_{IN(MIN)}$ and $V_{IN(MAX)}$. Calculate both of these sums.

Ideally, the losses at V_{IN(MIN)} should be roughly equal to losses at V_{IN(MAX)}, with lower losses in between. If the losses at V_{IN(MIN)} are significantly higher than the losses at V_{IN(MAX)}, consider increasing the size of N_H. Conversely, if the losses at V_{IN(MAX)} are significantly higher than the losses at V_{IN(MIN)}, consider reducing the size of N_H. If V_{IN} does not vary over a wide range, the minimum power dissipation occurs where the resistive losses equal the switching losses.

Choose a low-side MOSFET that has the lowest possible on-resistance (RDS(ON)), comes in a moderate-sized package (i.e., one or two 8-pin SOs, DPAK or D²PAK), and is reasonably priced. Make sure that the DL gate driver can supply sufficient current to support the gate charge and the current injected into the parasitic gate-to-drain capacitor caused by the high-side MOSFET turning on; otherwise, cross-conduction problems can occur.

MOSFET Power Dissipation

Worst-case conduction losses occur at the duty factor extremes. For the high-side MOSFET (N_H), the worst-case power dissipation due to resistance occurs at the minimum input voltage:

$$PD(N_{H}Resistive) = \left(\frac{V_{OUT}}{V_{IN}}\right) \left(\frac{I_{LOAD}}{\eta}\right)^{2} R_{DS(ON)}$$

Generally, a small high-side MOSFET is desired to reduce switching losses at high input voltages. However, the RDS(ON) required to stay within package power dissipation often limits how small the MOSFET can be. Again, the optimum occurs when the switching losses equal the conduction (RDS(ON)) losses. High-side switching losses do not usually become an issue until the input is greater than approximately 15V.

Calculating the power dissipation in high-side MOSFETs (N_H) due to switching losses is difficult since it must allow for difficult quantifying factors that influence the turn-on and turn-off times. These factors include the internal gate resistance, gate charge, threshold voltage, source inductance, and PC board layout characteristics. The following switching-loss calculation provides only a very rough estimate and is no substitute for breadboard evaluation, preferably including verification using a thermocouple mounted on N_H :

$$PD(N_{H} Switching) = \frac{\left(V_{IN(MAX)}\right)^{2} C_{RSS} f_{SW} I_{LOAD}}{I_{GATE} \eta}$$

where C_{RSS} is the reverse transfer capacitance of N_H and I_{GATE} is the peak gate-drive source/sink current (1A, typ).

Switching losses in the high-side MOSFET can become a heat problem when maximum AC adapter voltages are applied, due to the squared term in the C \times VIN 2 × fsw switching-loss equation. If the high-side MOSFET chosen for adequate RDS(ON) at low-battery voltages becomes extraordinarily hot when biased from VIN(MAX), consider choosing another MOSFET with lower parasitic capacitance.

For the low-side MOSFET (N_L), the worst-case power dissipation always occurs at maximum input voltage:

$$PD(N_{L}Resistive) = \left[1 - \left(\frac{V_{OUT}}{V_{IN(MAX)}}\right)\right] \left(\frac{I_{LOAD}}{\eta}\right)^{2} R_{DS(ON)}$$

The worst case for MOSFET power dissipation occurs under heavy overloads that are greater than ILOAD(MAX) but are not quite high enough to exceed the current limit and cause the fault latch to trip. To protect against this possibility, it is possible to "over design" the circuit to tolerate:

$$I_{LOAD} = \eta I_{VALLEY(MAX)} + \left(\frac{I_{LOAD(MAX)}LIR}{2}\right)$$

where IVALLEY(MAX) is the maximum "valley" current allowed by the current-limit circuit, including threshold

tolerance and on-resistance variation. The MOSFETs must have a relatively large heatsink to handle the overload power dissipation. Choose a Schottky diode (D1) with a forward voltage low enough to prevent the low-side MOSFET body diode from turning on during the dead time. As a general rule, select a diode with a DC current rating equal to $1/(3\eta)$ of the load current. This diode is optional and can be removed if efficiency is not critical.

Setting Voltage Positioning

Voltage positioning dynamically lowers the output voltage in response to the load current, reducing the processor's power dissipation. When the output is loaded, an internal operational amplifier (Figures 2 and 8) increases the signal fed back to the master's feedback input. The additional gain provided by the op amp allows the use of low-value, current-sense resistors, significantly reducing the power dissipated in the current-sense resistors rather than connecting the feedback voltage directly to the current-sense resistor. The load-transient response of this control loop is extremely fast, yet well controlled, so the amount of voltage change can be accurately confined within the limits stipulated in the microprocessor power-supply guidelines. To understand the benefits of dynamically adjusting the output voltage, see the Voltage Positioning and Effective Efficiency section.

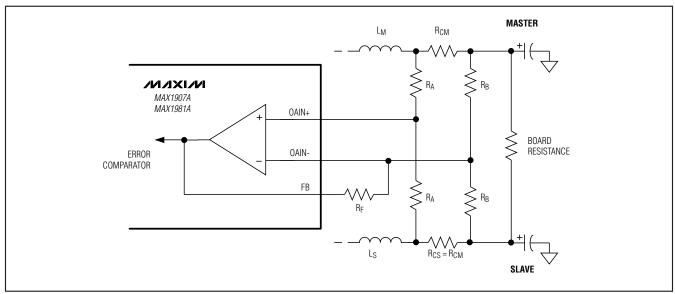


Figure 8. Voltage Positioning Gain

The voltage-positioned circuit determines the load current from the voltage across the current-sense resistors (RSENSE = RCM = RCS) connected between the inductors and output capacitors, as shown in Figure 8. The voltage drop may be determined by the following equation:

$$V_{VPS} = \left(1 + \frac{\eta R_F}{R_B}\right) \left(\frac{I_{LOAD}}{\eta}\right) R_{SENSE}$$

$$V_{VPS} = \left(\frac{1}{\eta} + \frac{R_F}{R_B}\right) I_{LOAD} R_{SENSE}$$

where η is the number of phases summed together. When the slave controller is disabled, the current-sense summation maintains the proper voltage-positioned slope. Select the positive input-summing resistors using the following equation:

 $R_A = R_B II(\eta R_F)$

Applications Information

Voltage Positioning and Effective Efficiency

Powering new mobile processors requires careful attention to detail to reduce cost, size, and power dissipation. As CPUs became more power hungry, it was recognized that even the fastest DC-DC converters were inadequate to handle the transient power requirements. After a load transient, the output instantly changes by ESRCOUT \times ΔI_{LOAD} . Conventional DC-DC converters respond by regulating the output voltage back to its nominal state after the load transient occurs (Figure 9). However, the CPU only requires that the output voltage remain above a specified minimum value. Dynamically positioning the output voltage to this lower limit allows the use of fewer output capacitors and reduces power consumption under load.

For a conventional (non-voltage-positioned) circuit, the total voltage change is:

$$V_{P-P1} = 2 \times (ESR_{COUT} \times \Delta I_{LOAD}) + V_{SAG} + V_{SOAR}$$

where V_{SAG} and V_{SOAR} are defined in Figure 10. Setting the converter to regulate at a lower voltage when under load allows a larger voltage step when the output current suddenly decreases (Figure 9). So the total voltage change for a voltage-positioned circuit is:

 $V_{P-P2} = 2 \times (ESR_{COUT} \times \Delta I_{LOAD}) + V_{SAG} + V_{SOAR}$

where V_{SAG} and V_{SOAR} are defined in the *Design Procedure* section. Since the amplitudes are the same for both circuits (V_{P-P1} = V_{P-P2}), the voltage-positioned circuit tolerates twice the ESR. Since the ESR specification is achieved by paralleling several capacitors, fewer units are needed for the voltage-positioned circuit.

An additional benefit of voltage positioning is reduced power consumption at high load currents. Since the output voltage is lower under load, the CPU draws less current. The result is lower power dissipation in the CPU, although some extra power is dissipated in RSENSE. For a nominal 1.4V, 30A output (RLOAD = $46.7 m\Omega$), reducing the output voltage 7.1% gives an output voltage of 1.3V and an output current of 27.8A. Given these values, CPU power consumption is reduced from 42W to 36.1W. The additional power consumption of RSENSE is:

$$1.5 \text{m}\Omega \times (27.8 \text{A})^2 = 1.16 \text{W},$$

which results in an overall power savings of:

$$42W - (36.1W + 1.16W) = 4.7W.$$

In effect, 5.9W of CPU dissipation is saved and the power supply dissipates much of the savings, but both the net savings and the transfer of dissipation away from the hot CPU are beneficial. Effective efficiency is defined as the efficiency required of a non-voltage-positioned circuit to equal the total dissipation of a voltage-positioned circuit for a given CPU operating condition.

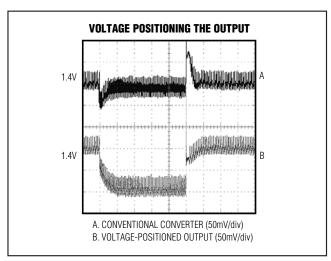


Figure 9. Voltage Positioning the Output

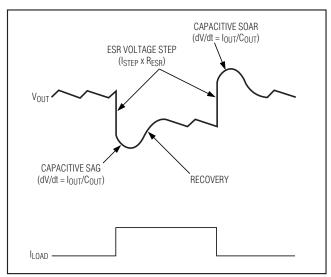


Figure 10. Transient Response Regions

Calculate effective efficiency as follows:

- 1) Start with the efficiency data for the positioned circuit (VIN, IIN, VOUT, IOUT).
- 2) Model the load resistance for each data point:

$$R_{LOAD} = V_{OUT} / I_{OUT}$$

 Calculate the output current that would exist for each R_{LOAD} data point in a non-positioned application:

where $V_{NP} = 1.6V$ (in this example).

- 4) Calculate effective efficiency as:
 - Effective efficiency = $(V_{NP} \times I_{NP}) / (V_{IN} \times I_{IN})$ = calculated non-positioned power output divided by the measured voltage-positioned power input.
- 5) Plot the efficiency data point at the non-positioned current, I_{NP}.

The effective efficiency of voltage-positioned circuits is shown in the *Typical Operating Characteristics*.

One-Stage (Battery Input) vs. Two-Stage (5V Input) Applications

The MAX1907A/MAX1981A can be used with a direct battery connection (one stage) or can obtain power from a regulated 5V supply (two stage). Each approach has advantages, and careful consideration should go into the selection of the final design.

The one-stage approach offers smaller total inductor size and fewer capacitors overall due to the reduced demands on the 5V supply. Due to the high input voltage, the one-stage approach requires lower DC input currents, reducing input connection/bus requirements and power dissipation due to input resistance. The transient response of the single stage is better due to the ability to ramp the inductor current faster. The total efficiency of a single stage is better than the two-stage approach.

The two-stage approach allows flexible placement due to smaller circuit size and reduced local power dissipation. The power supply can be placed closer to the CPU for better regulation and lower I²R losses from PC board traces. Although the two-stage design has slower transient response than the single stage, this can be offset by the use of a voltage-positioned converter.

Ceramic Output Capacitor Applications

Ceramic capacitors have advantages and disadvantages. They have ultra-low ESR and are noncombustible, relatively small, and nonpolarized. However, they are also expensive and brittle, and their ultra-low ESR characteristic can result in excessively high ESR zero frequencies. In addition, their relatively low capacitance value can cause output overshoot when stepping from full-load to no-load conditions, unless a small inductor value is used (high switching frequency), or there are some bulk tantalum or electrolytic capacitors in parallel to absorb the stored inductor energy. In some cases, there may be no room for electrolytics, creating a need for a DC-DC design that uses nothing but ceramics.

The MAX1907A/MAX1981A can take full advantage of the small size and low ESR of ceramic output capacitors in a voltage-positioned circuit. The addition of the positioning resistor increases the ripple at FB, lowering the effective ESR zero frequency of the ceramic output capacitor.

Output overshoot (Vsoar) determines the minimum output capacitance requirement (see the *Output Capacitor Selection* section). Often the switching frequency is increased to 550kHz, and the inductor value is reduced to minimize the energy transferred from inductor to capacitor during load-step recovery. The efficiency penalty for operating at 550kHz is about 2% when compared to the 300kHz circuit, primarily due to the high-side MOSFET switching losses.

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PC Board Layout Guidelines

Careful PC board layout is critical to achieve low switching losses and clean, stable operation. The switching power stage requires particular attention (Figure 11). If possible, mount all of the power components on the top side of the board with their ground terminals flush against one another. Follow these guidelines for good PC board layout:

- Keep the high-current paths short, especially at the ground terminals. This is essential for stable, jitterfree operation.
- 2) Connect all analog grounds to a separate solid copper plane, which connects to the GND pin of the MAX1907A/MAX1981A. This includes the VCC bypass capacitor, REF bypass capacitor, compensation (CC) capacitor, and the resistive-dividers connected to ILIM and POS/NEG.
- 3) The master controller should also have a separate analog ground. Return the appropriate noise sensitive components to this plane. Since the reference in the master is sometimes connected to the slave, it may be necessary to couple the analog ground in

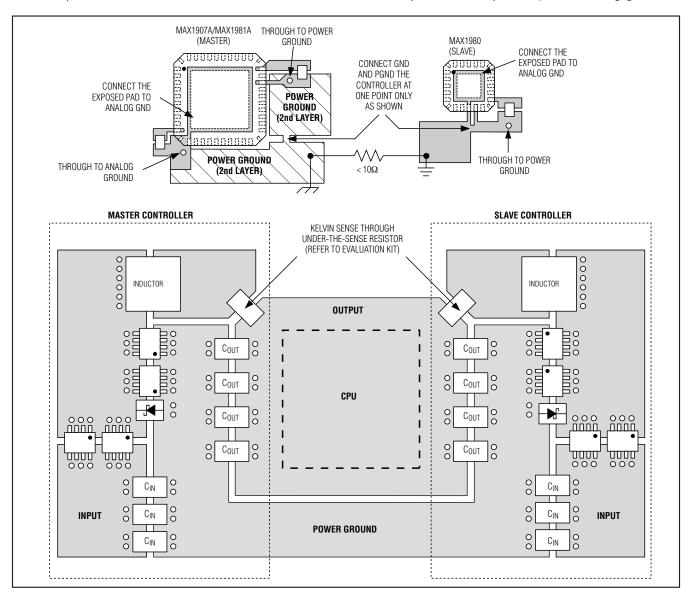


Figure 11. PC Board Layout Example

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- the master to the analog ground in the slave to prevent ground offsets. A low value ($\leq 10\Omega$) resistor is sufficient to link the two grounds.
- 4) Keep the power traces and load connections short. This is essential for high efficiency. The use of thick copper PC boards (2oz vs. 1oz) can enhance full-load efficiency by 1% or more. Correctly routing PC board traces is a difficult task that must be approached in terms of fractions of centimeters, where $1m\Omega$ of excess trace resistance causes a measurable efficiency penalty.
- 5) Keep the high-current, gate-driver traces (DL, DH, LX, and BST) short and wide to minimize trace resistance and inductance. This is essential for high-power MOSFETs that require low-impedance gate drivers to avoid shoot-through currents.
- 6) CSP, CSN, OAIN+, and OAIN- connections for current limiting and voltage positioning must be made using Kelvin sense connections to guarantee the current-sense accuracy.
- 7) When trade-offs in trace lengths must be made, it is preferable to allow the inductor charging path to be made longer than the discharge path. For example, it is better to allow some extra distance between the input capacitors and the high-side MOSFET than to allow distance between the inductor and the lowside MOSFET or between the inductor and the output filter capacitor.
- 8) Route high-speed switching nodes away from sensitive analog areas (REF, COMP, ILIM, CSP, CSN, etc.). Make all pin-strap control input connections (SHDN, ILIM, B0-B2, S0-S2, TON) to analog ground or VCC rather than power ground or VDD.

Layout Procedure

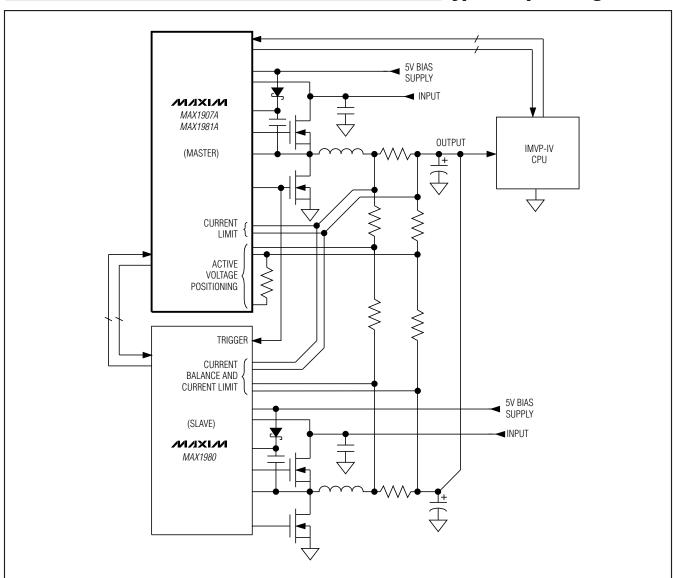
Place the power components first, with ground terminals adjacent (low-side MOSFET source, C_{IN}, C_{OUT}, and D1 anode). If possible, make all these connections on the top layer with wide, copper-filled areas.

- Mount the controller IC adjacent to the low-side MOSFET. The DL gate trace must be short and wide (50mils to 100mils wide if the MOSFET is 1 inch from the controller IC).
- Group the gate-drive components (BST diode and capacitor, V_{DD} bypass capacitor) together near the controller IC.
- 4) Make the DC-DC controller ground connections as shown in Figure 1. This diagram can be viewed as having four separate ground planes: input/output ground (where all the high-power components go), the power ground plane (where the PGND pin and V_{DD} bypass capacitor go), the master's analog ground plane (where sensitive analog components such as the master's GND pin and VCC bypass capacitor go), and the slave's analog ground plane (where the slave's GND pin and V_{CC} bypass capacitor go). The master's GND plane must meet the PGND plane only at a single point directly beneath the IC. Similarly, the slave's GND plane must meet the PGND plane only at a single point directly beneath the IC. The respective master and slave ground planes should connect to the highpower output ground with a short metal trace from PGND to the source of the low-side MOSFET (the middle of the star ground). This point must also be very close to the output capacitor ground terminal.
- 5) Connect the output power planes (VCORE and system ground planes) directly to the output filter capacitor positive and negative terminals with multiple vias. Place the entire DC-DC converter circuit as close to the CPU as is practical.

Chip Information

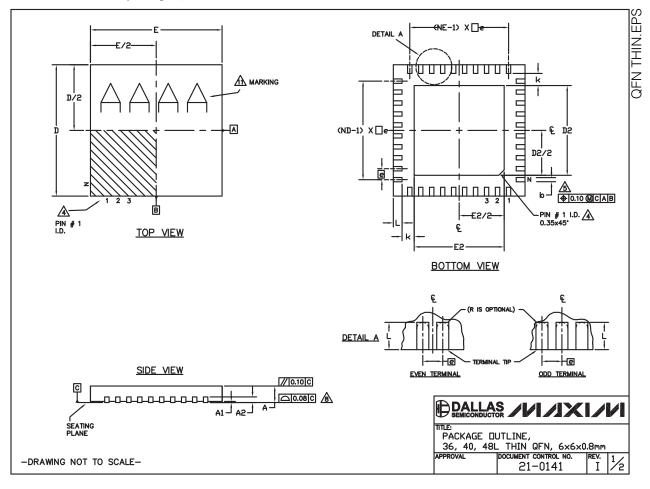
TRANSISTOR COUNT: 8713
PROCESS: BICMOS

Typical Operating Circuit



Package Information

(The package drawing(s) in this data sheet may not reflect the most current specifications. For the latest package outline information, go to **www.maxim-ic.com/packages**.)



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Package Information (continued)

(The package drawing(s) in this data sheet may not reflect the most current specifications. For the latest package outline information, go to **www.maxim-ic.com/packages**.)

COMMON DIMENSIONS												
PKG.	36L 6x6			40L 6x6			48L 6x6					
SYMBOL	MIN.	NOM.	MAX.	MIN.	NOM.	MAX.	MIN.	NOM.	MAX.			
Α	0.70	0.75	0.80	0.70	0.75	0.80	0.70	0.75	0.80			
A1	0	0.02	0.05	0	0.02	0.05	0	_	0.05			
A2	0.20 REF.			0.20 REF.			0.20 REF.					
b	0.20	0.25	0.30	0.20	0.25	0.30	0.15	0.20	0.25			
D	5.90	6.00	6.10	5.90	6.00	6.10	5.90	6.00	6.10			
E	5.90	6.00	6.10	5.90	6.00	6.10	5.90	6.00	6.10			
е	0.50 BSC.			0.50 BSC.			0.40 BSC.					
k	0.25	_	_	0.25	-	-	0.25	_	_			
L	0.35	0.50	0.65	0.30	0.40	0.50	0.30	0.40	0.50			
N	36			40			48					
ND	9			10			12					
NE	9			10			12					
JEDEC	WJJD-1			WJJD-2			-					

EXPOSED PAD VARIATIONS												
PKG.		D2		E2								
CODES	MIN.	NOM.	MAX.	MIN.	NOM.	MAX.						
T3666-2	3.60	3.70	3.80	3.60	3.70	3.80						
T3666-3	3.60	3.70	3.80	3.60	3.70	3.80						
T3666N-1	3.60	3.70	3.80	3.60	3.70	3.80						
T3666MN-1	3.60	3.70	3.80	3.60	3.70	3.80						
T4066-2	4.00	4.10	4.20	4.00	4.10	4.20						
T4066-3	4.00	4.10	4.20	4.00	4.10	4.20						
T4066-5	4.00	4.10	4.20	4.00	4.10	4.20						
T4866-1	4.40	4.50	4.60	4.40	4.50	4.60						
T4866N-1	4.40	4.50	4.60	4.40	4.50	4.60						
T4866-2	4.40	4.50	4.60	4.40	4.50	4.60						

NOTES:

- 1. DIMENSIONING & TOLERANCING CONFORM TO ASME Y14.5M-1994.
- 2. ALL DIMENSIONS ARE IN MILLIMETERS. ANGLES ARE IN DEGREES.
- 3. N IS THE TOTAL NUMBER OF TERMINALS.
- THE TERMINAL #1 IDENTIFIER AND TERMINAL NUMBERING CONVENTION SHALL CONFORM TO JESD 95-1 SPP-012. DETAILS OF TERMINAL #1 IDENTIFIER ARE OPTIONAL, BUT MUST BE LOCATED WITHIN THE ZONE INDICATED. THE TERMINAL #1 IDENTIFIER MAY BE EITHER A MOLD OR MARKED FEATURE.
- DIMENSION 6 APPLIES TO METALLIZED TERMINAL AND IS MEASURED BETWEEN 0.25mm AND 0.30mm FROM TERMINAL TIP.
- 6. ND AND NE REFER TO THE NUMBER OF TERMINALS ON EACH D AND E SIDE RESPECTIVELY.
- 7. DEPOPULATION IS POSSIBLE IN A SYMMETRICAL FASHION.
- \land COPLANARITY APPLIES TO THE EXPOSED HEAT SINK SLUG AS WELL AS THE TERMINALS.
- DRAWING CONFORMS TO JEDEC MO220, EXCEPT FOR 0.4mm LEAD PITCH PACKAGE T4866-1.
- 10. WARPAGE SHALL NOT EXCEED 0.10mm.
- MARKING IS FOR PACKAGE DRIENTATION REFERENCE ONLY.
- 12. NUMBER OF LEADS SHOWN FOR REFERENCE ONLY.
- 13. ALL DIMENSIONS APPLY TO BOTH LEADED (-) AND POFREE (+) PKG. CODES.

-DRAWING NOT TO SCALE-



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